

O R I G I N A L S

1/44

11790871

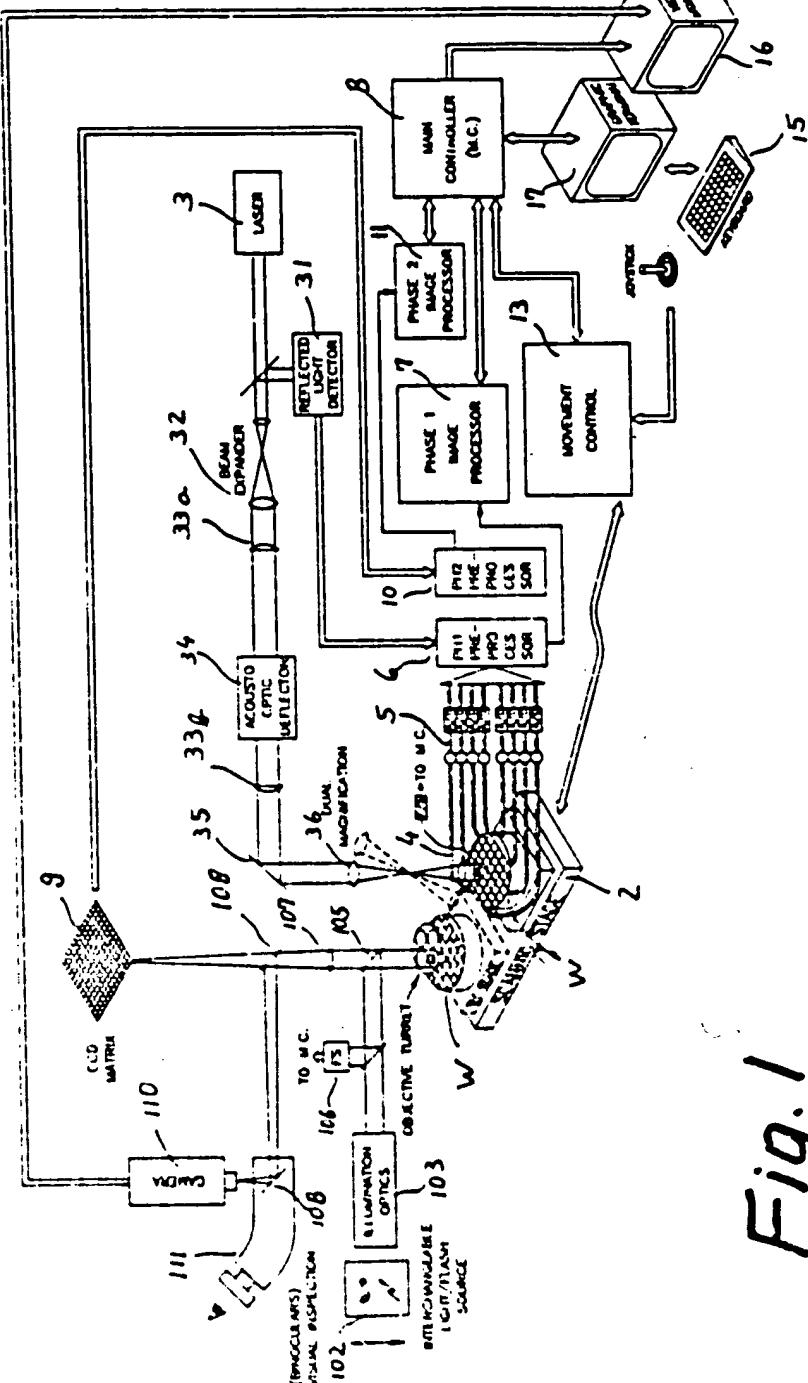
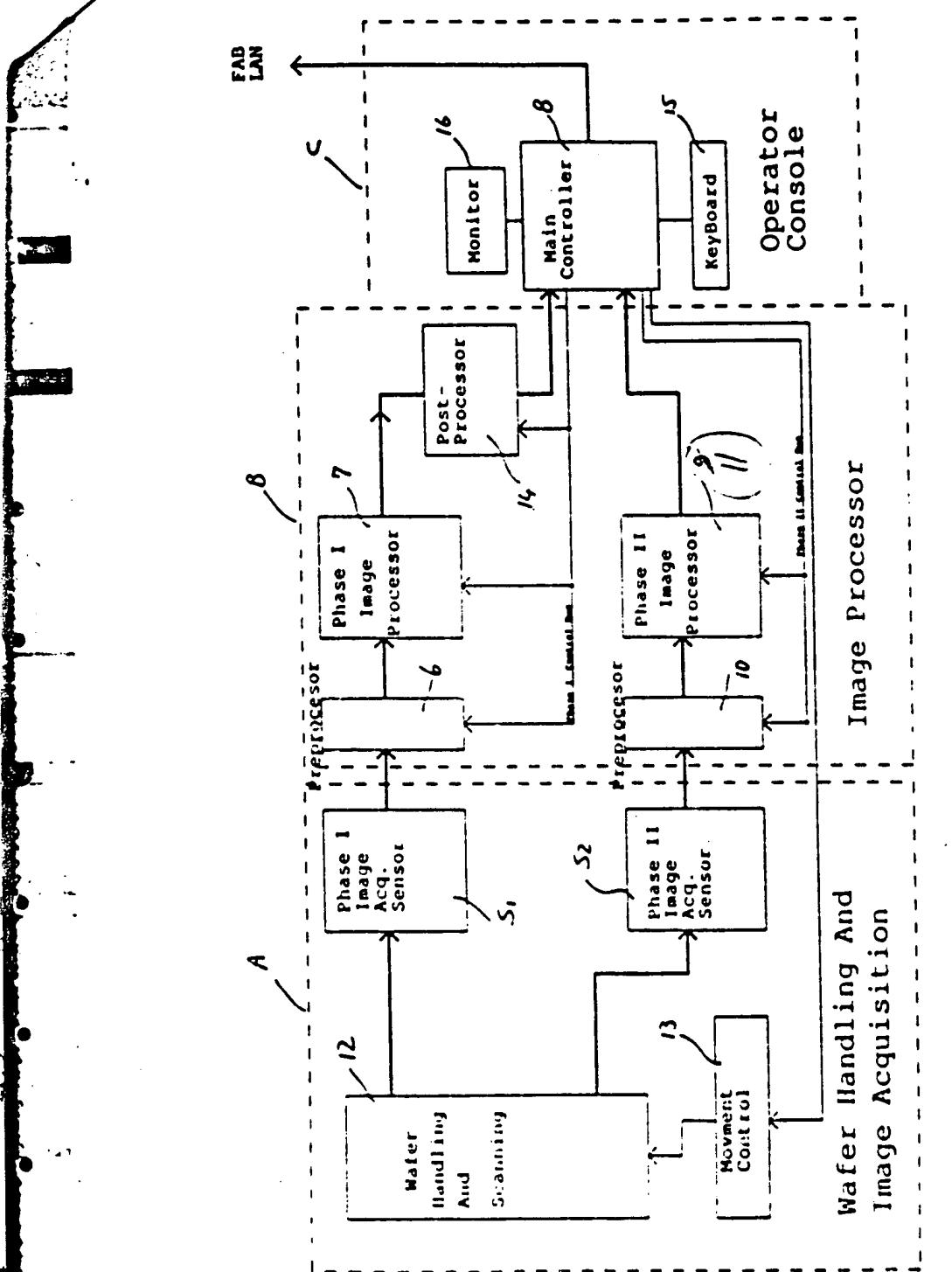


Fig. 1

BEST AVAILABLE COPY

11/790871

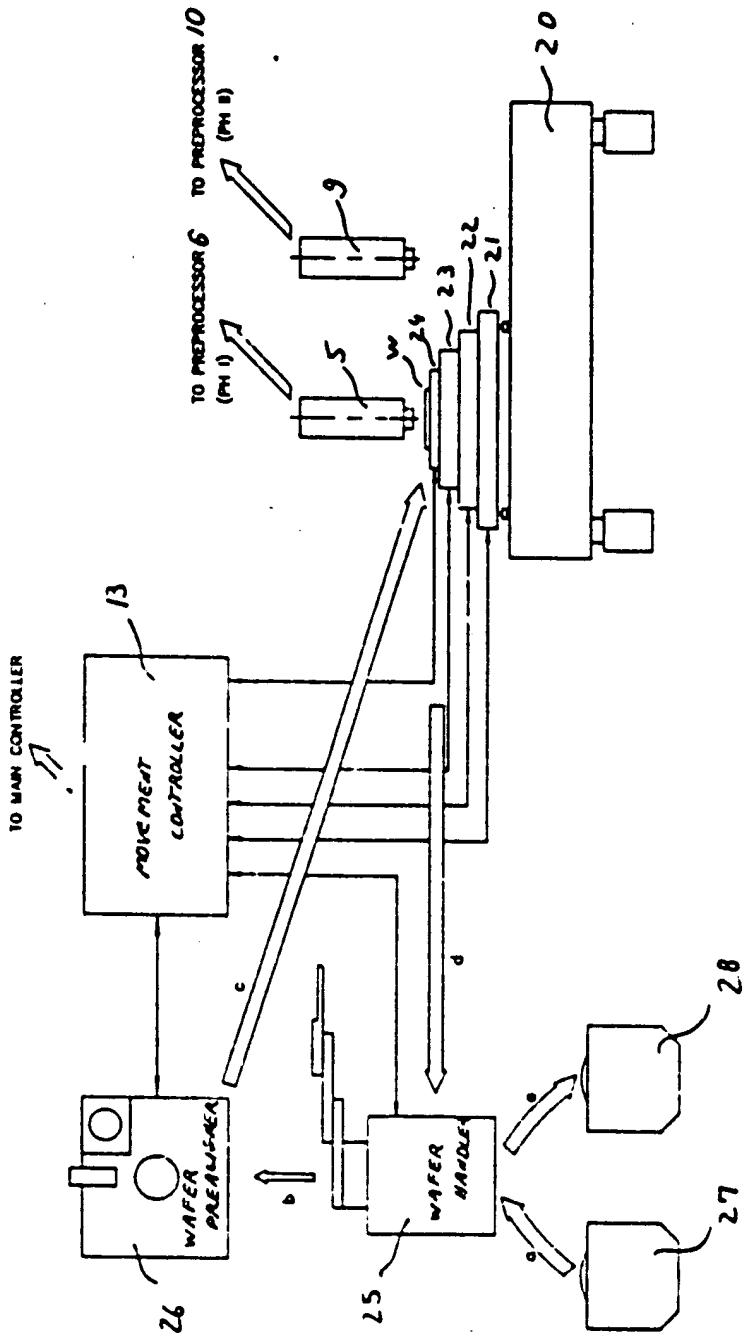
Fig. 2

System Block Diagram

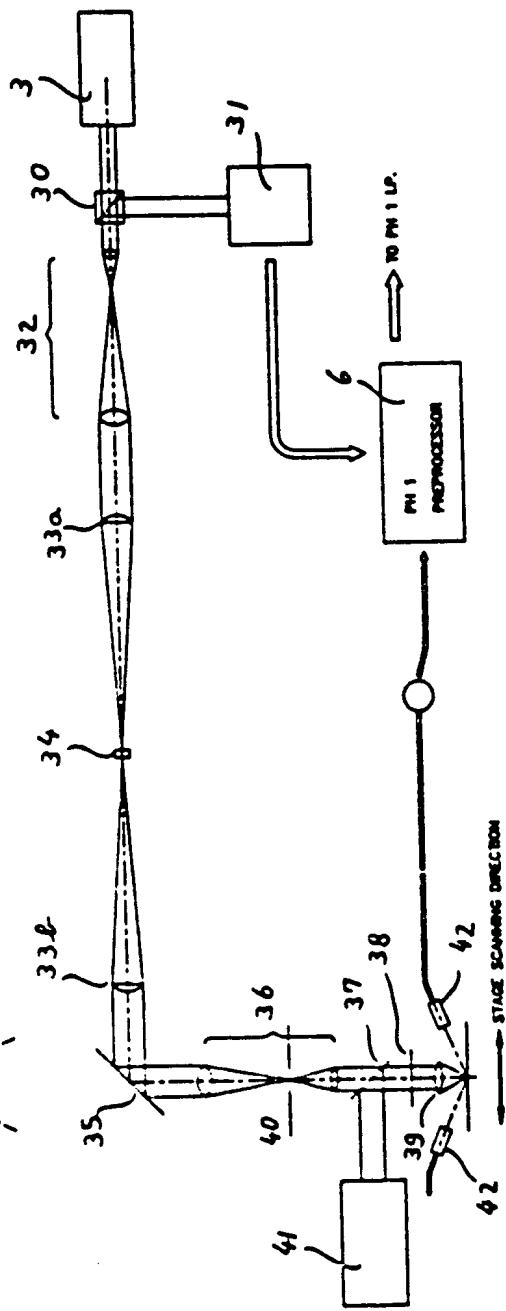
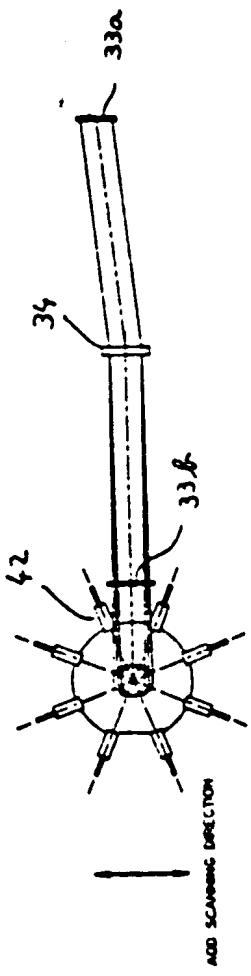
3/41

11/790871

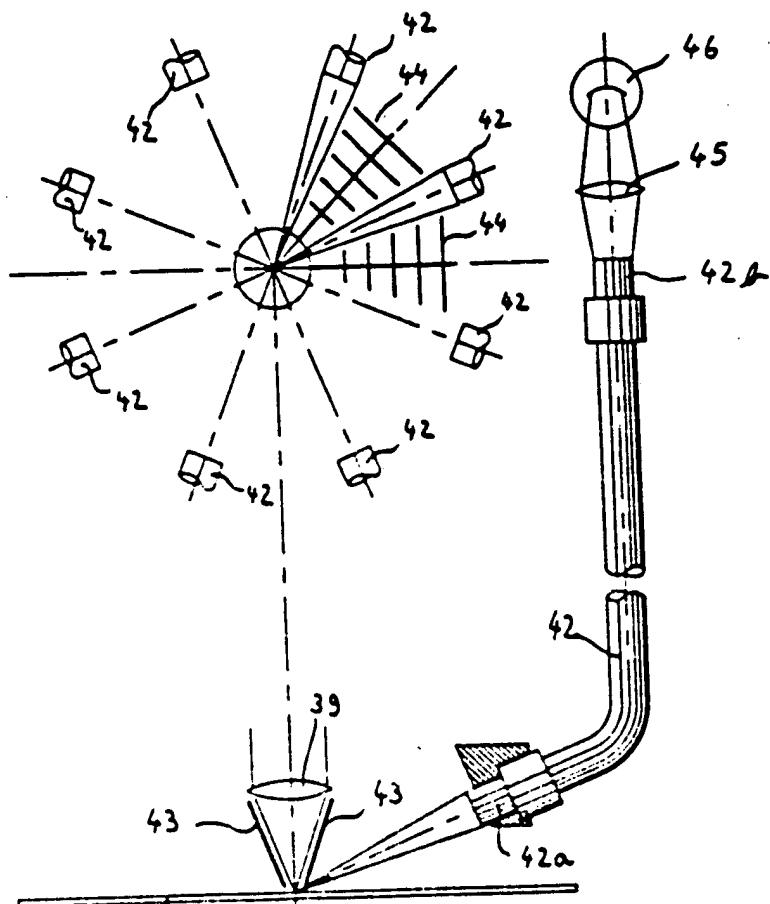
Fig 3



11/790871

Fig 5Fig 4

11/790871

Fig 6Fig. 7

6/41

11/790871

Fig 6a

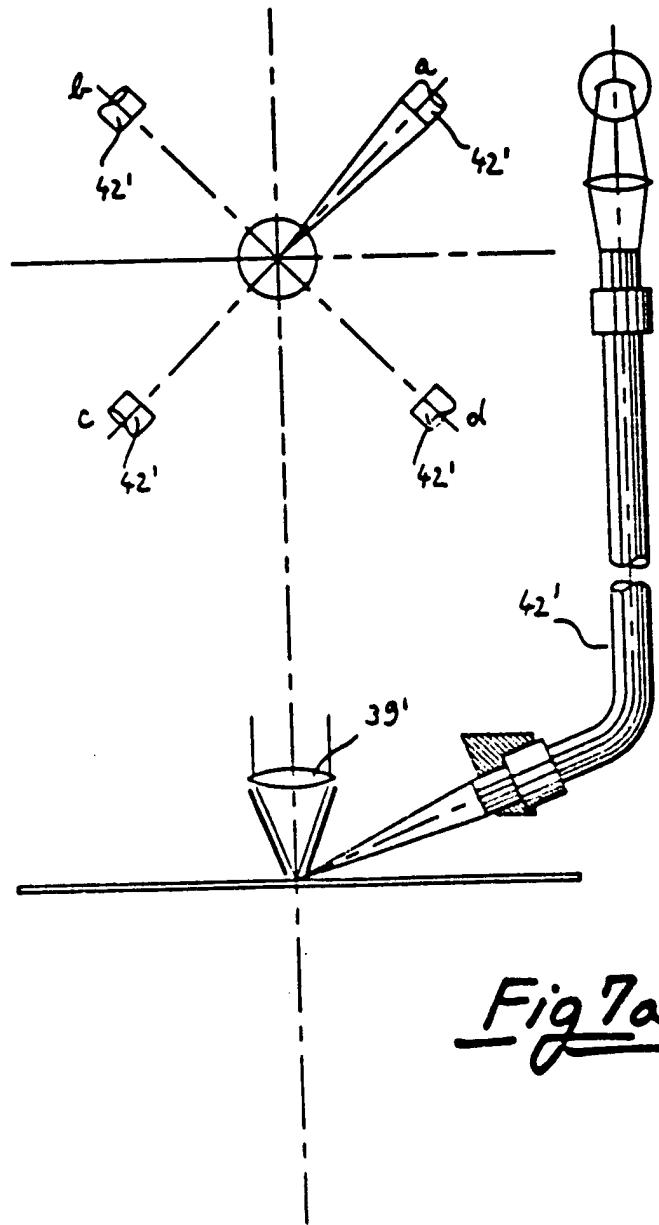
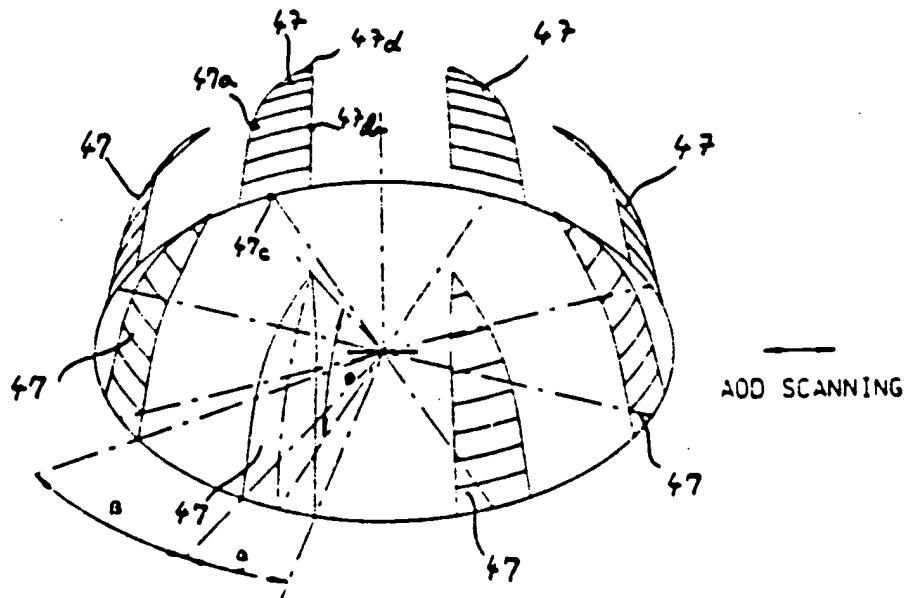


Fig 7a

11/790871

Fig. 8



8/41

290871

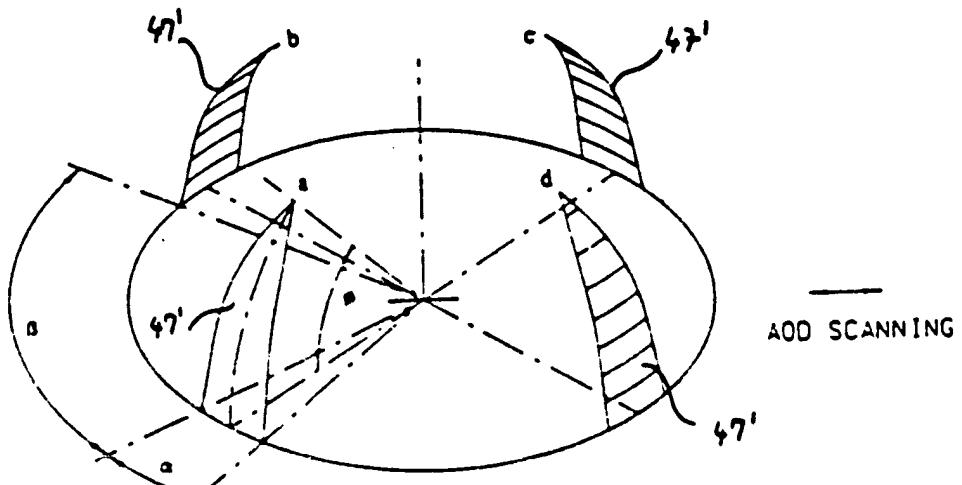


Fig 8a

9/41

11/790871

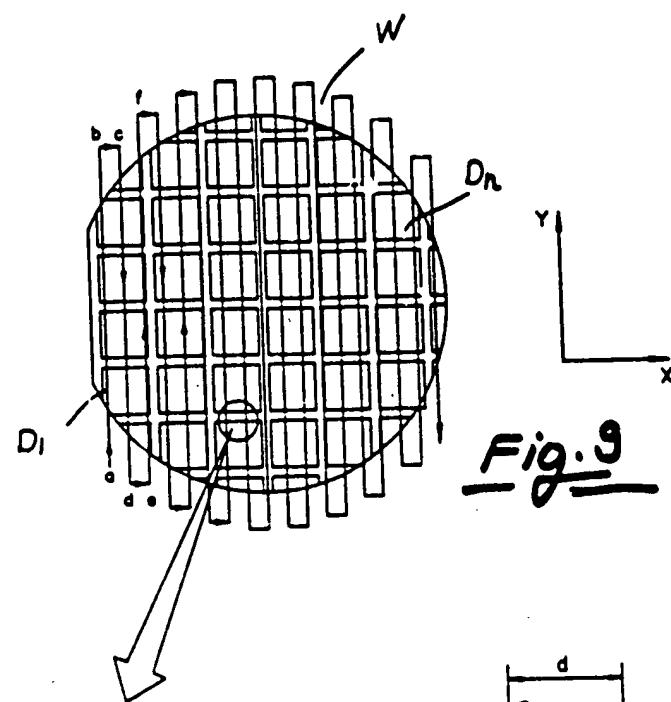


Fig. 9

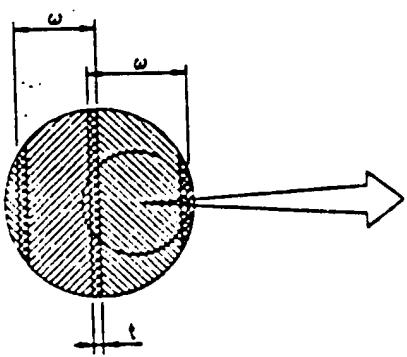


Fig. 10

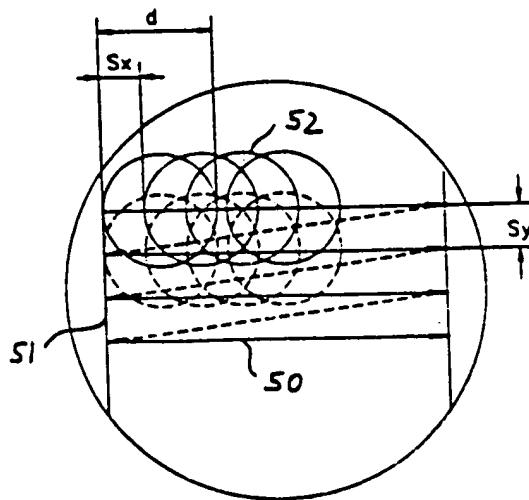


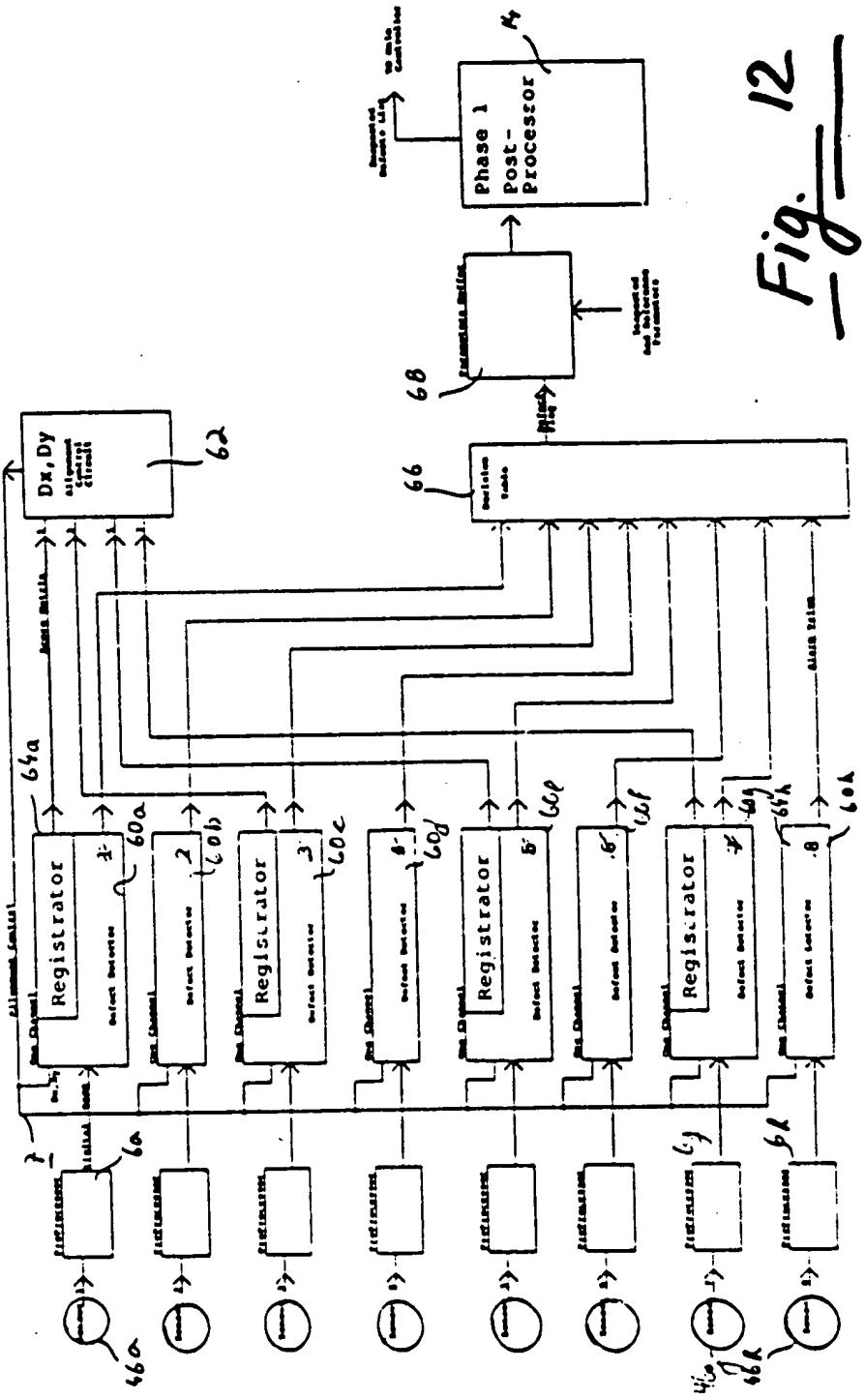
Fig. 11

10/91

11/790871

Fig. 12

Phase 1 I.P. Overall Functional Block Diagram



11/41

11/790871

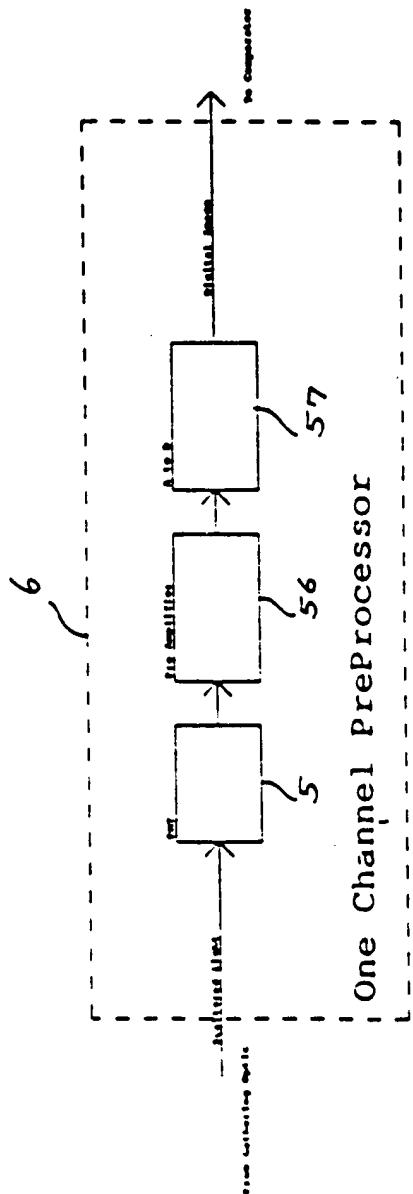
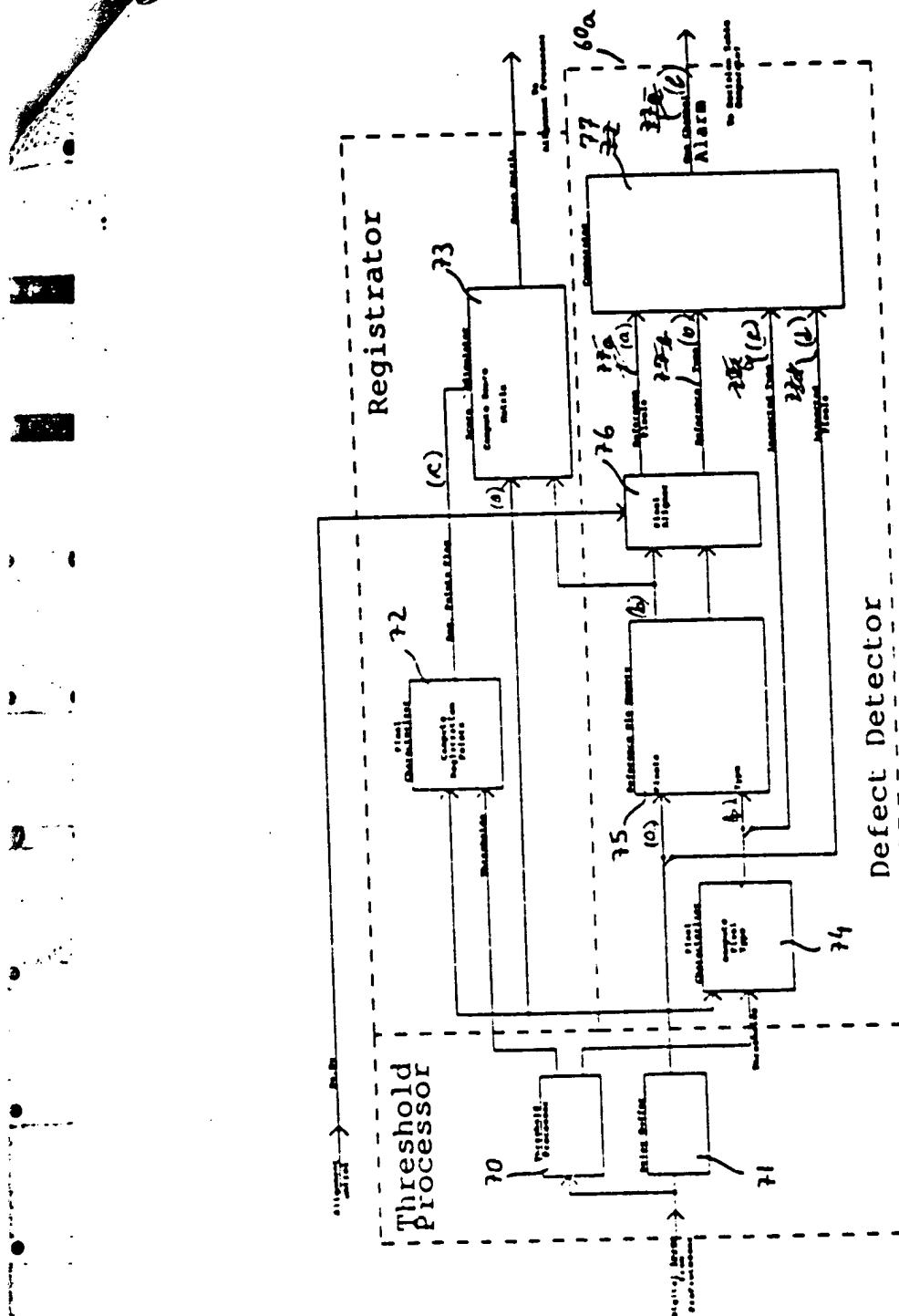


Fig. 13

12/41

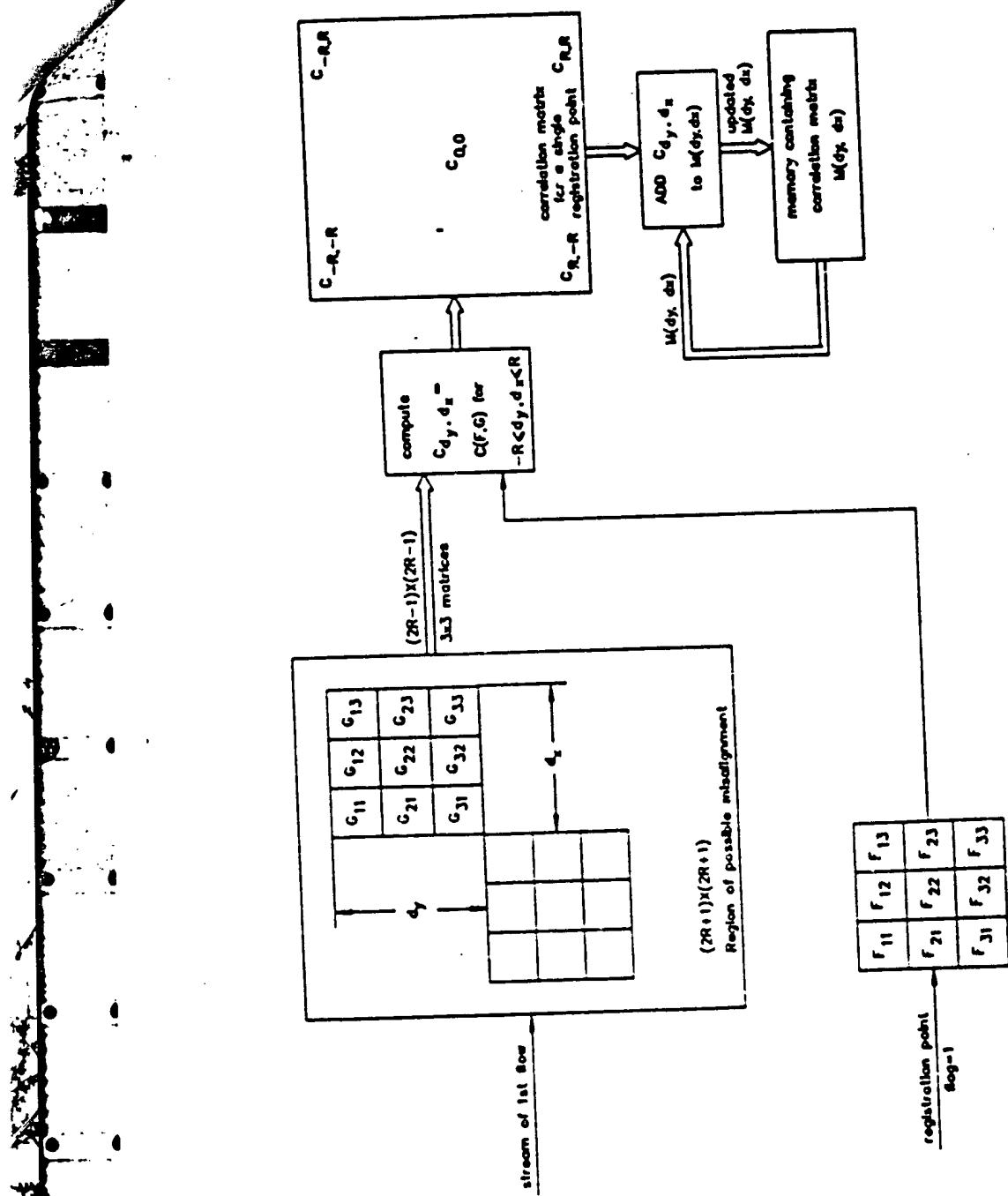
11/790871



One Channel I.P. Block Diagram

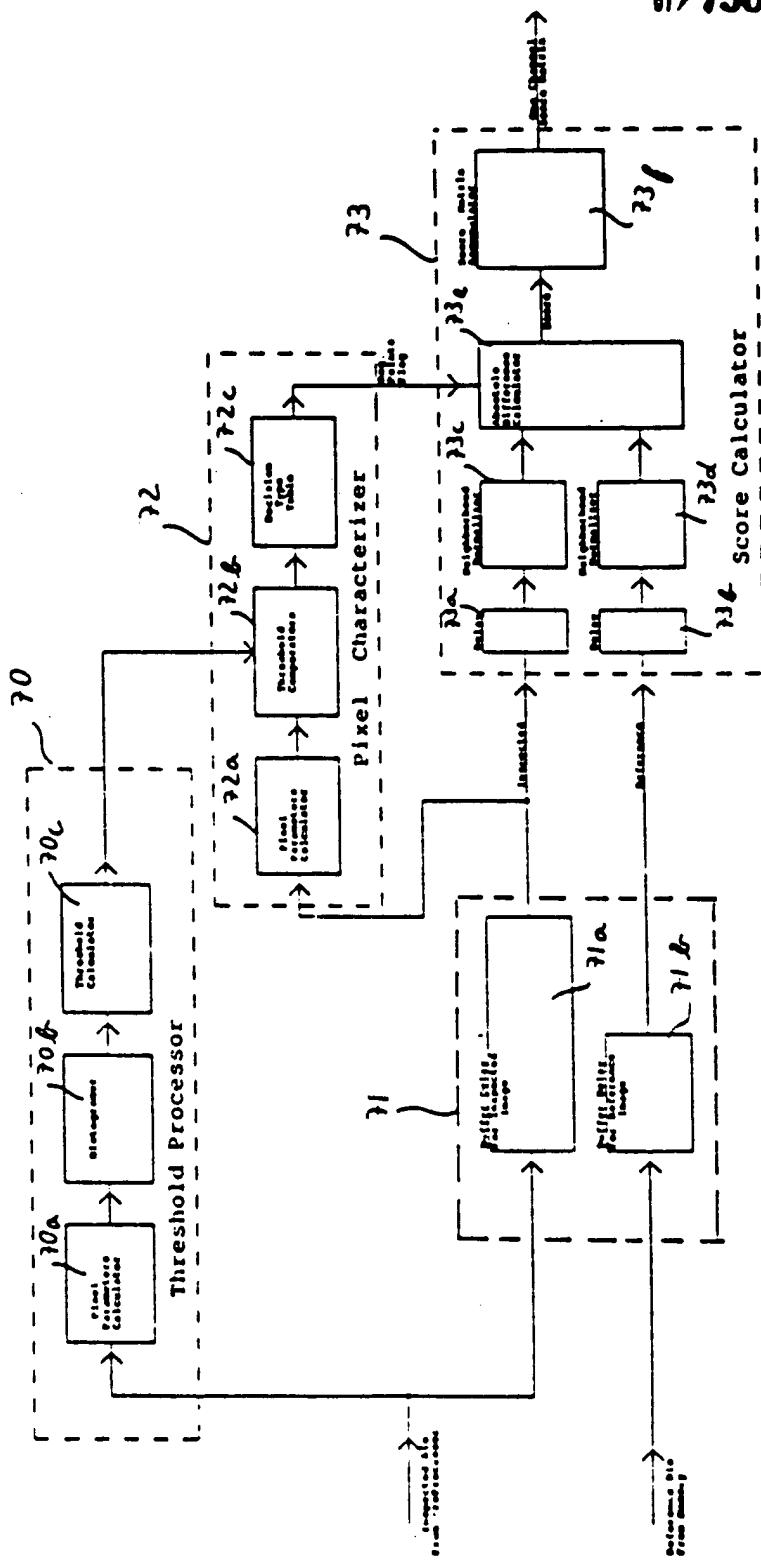
Fig. 14

11/790871

Fig. 14a

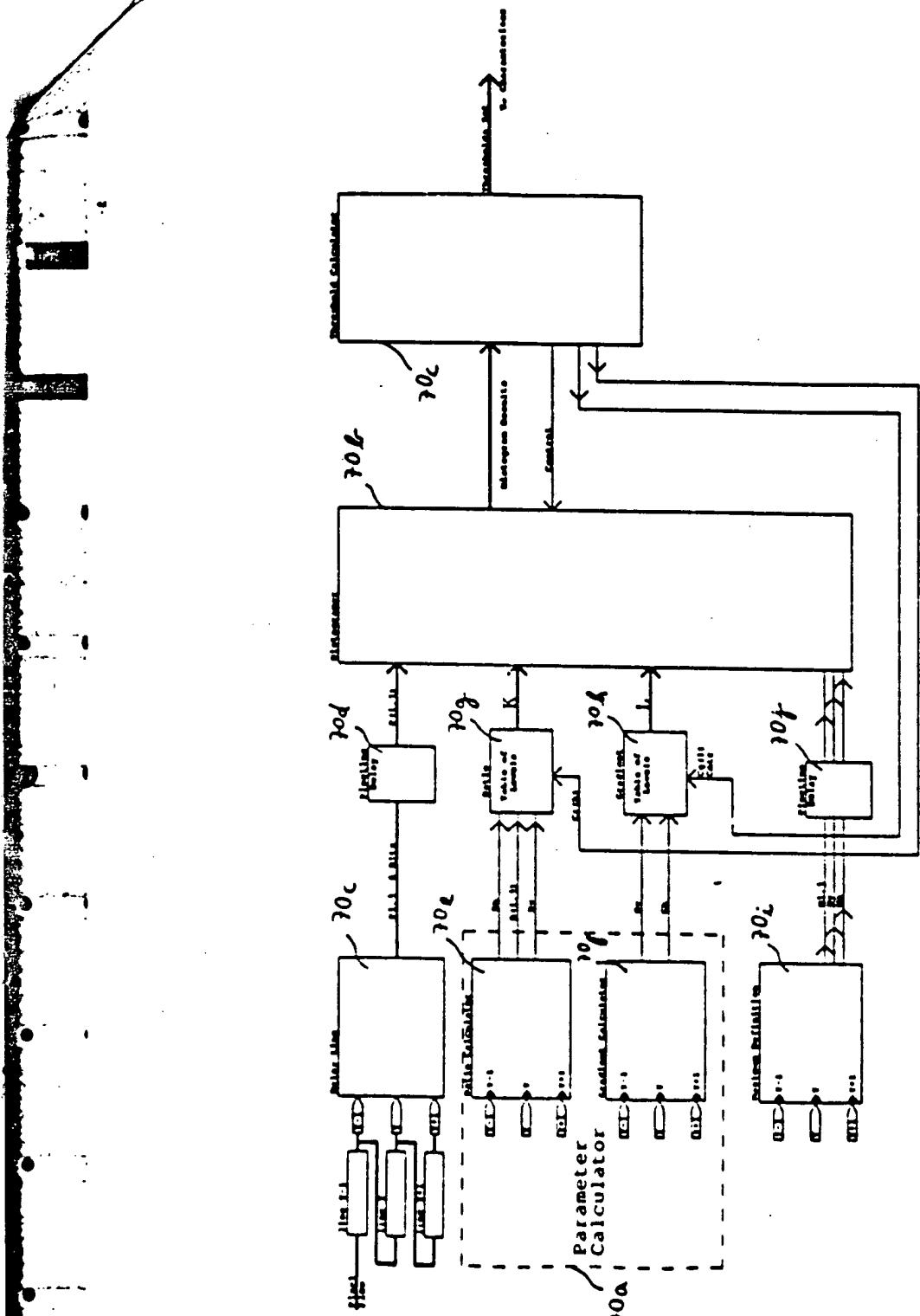
14/41

11/790871



Registrar Block Diagram

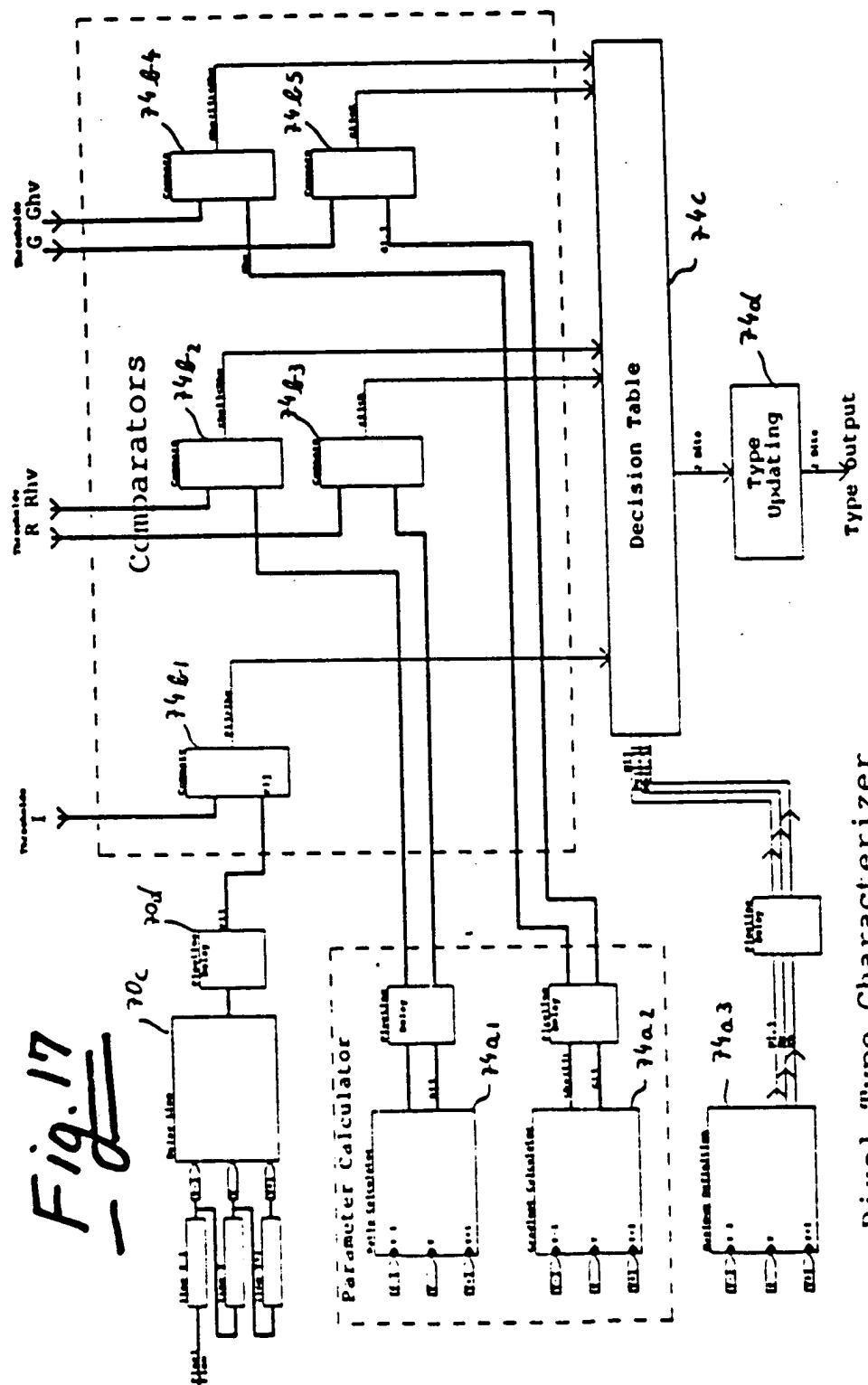
Fig. 15



Threshold Processor Block Diagram

Fig. 16

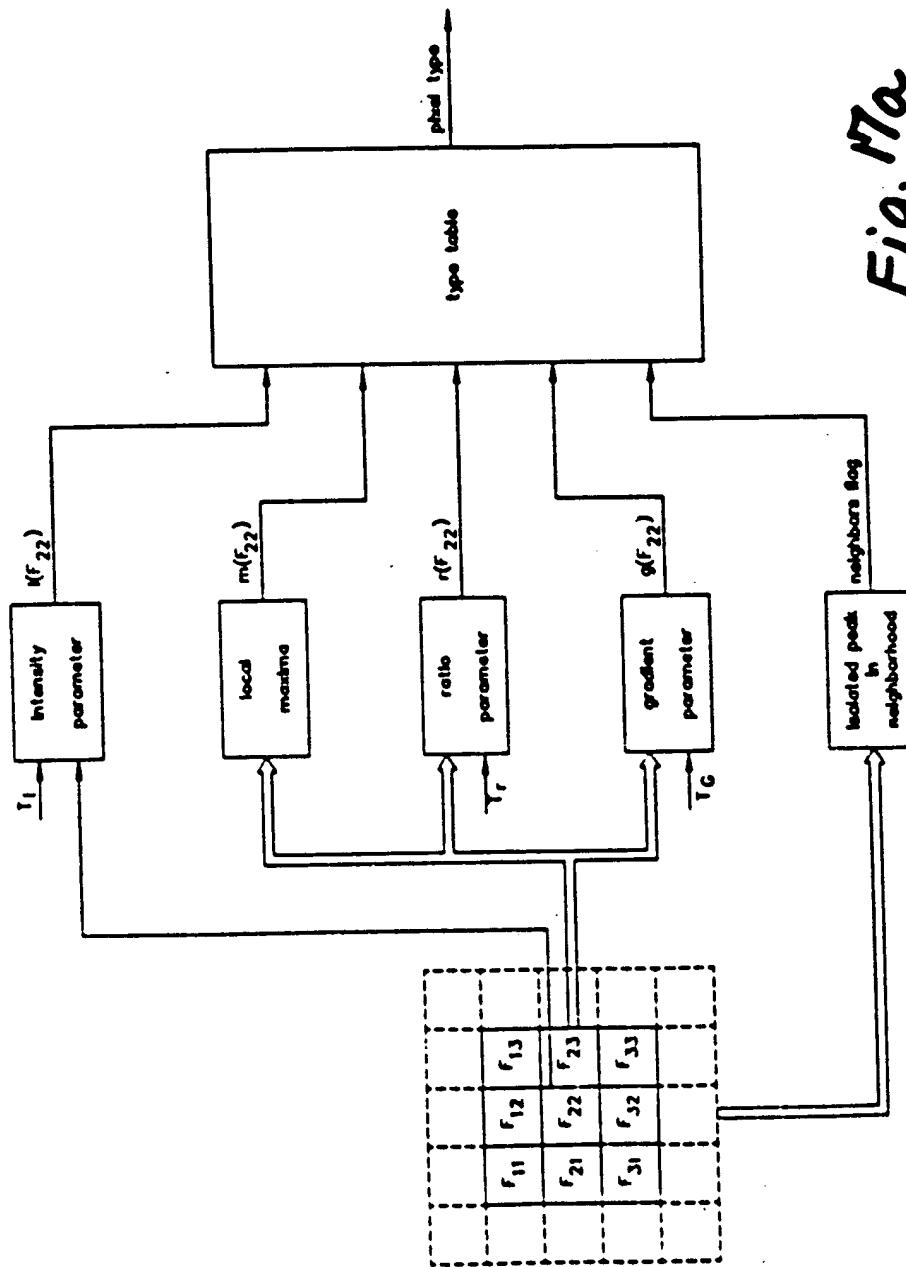
11/790871



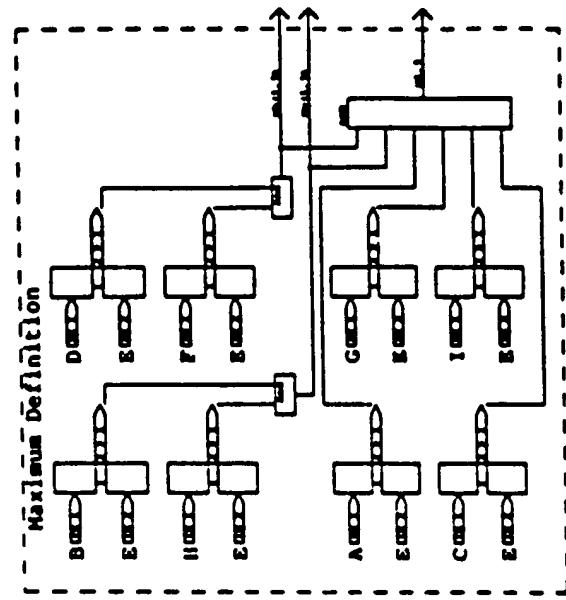
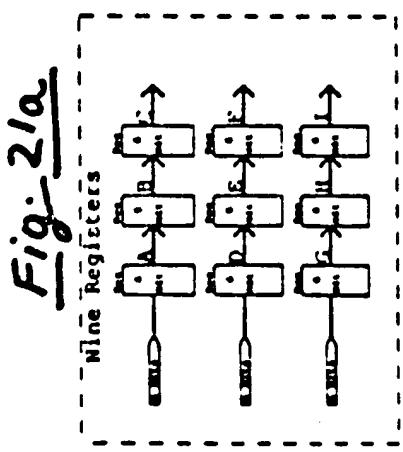
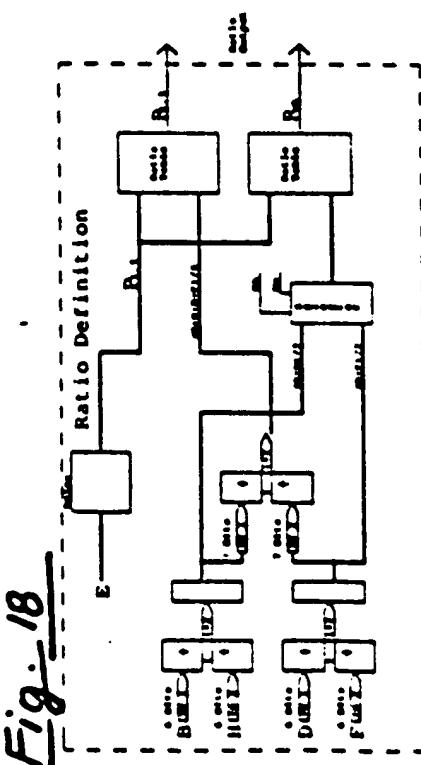
Pixel Type Characterizer

11/790871

Fig. 17a



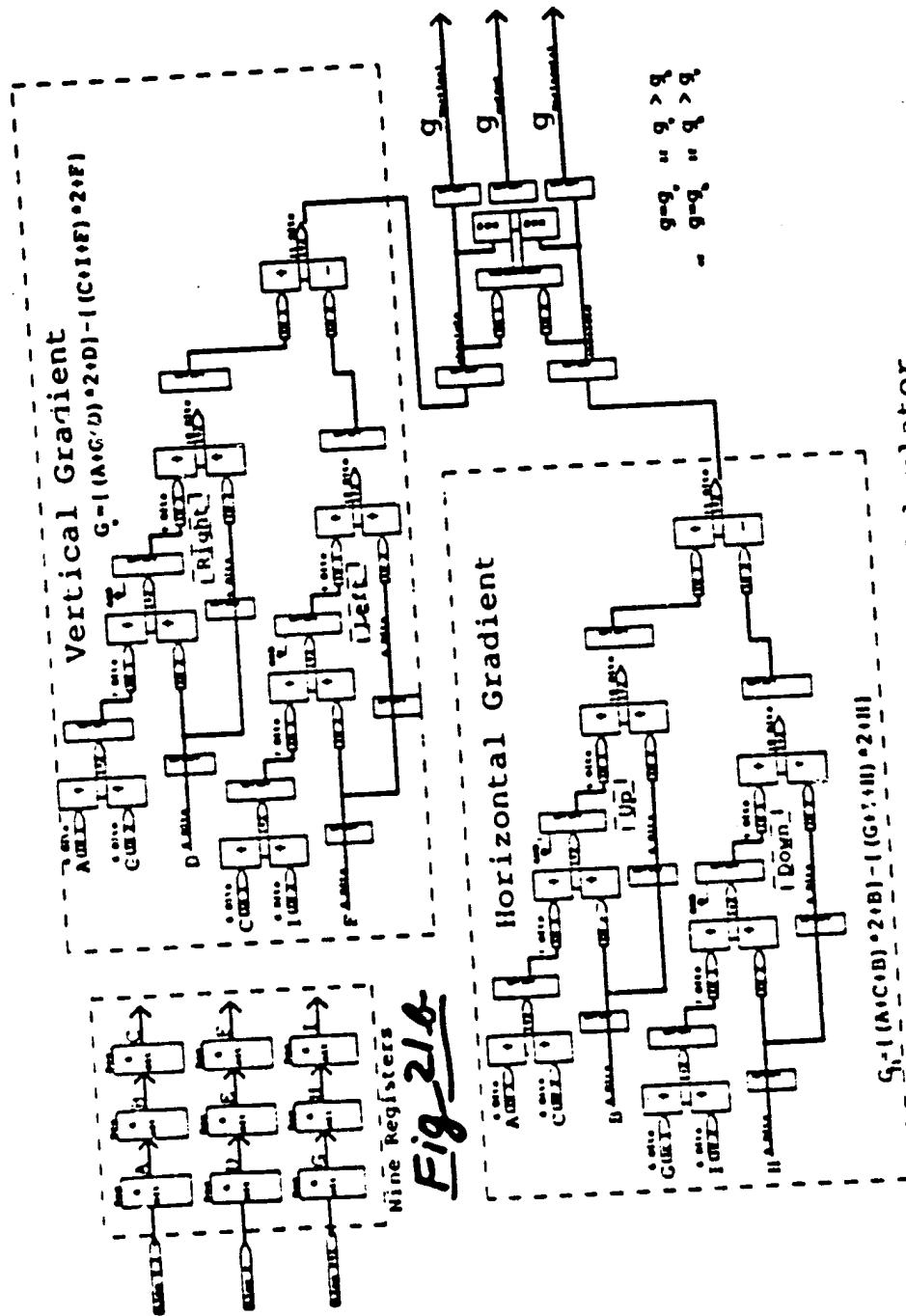
11/790871

Fig. 20Fig. 2/aFig. 18

Ratio And Maximum Definition

19/41

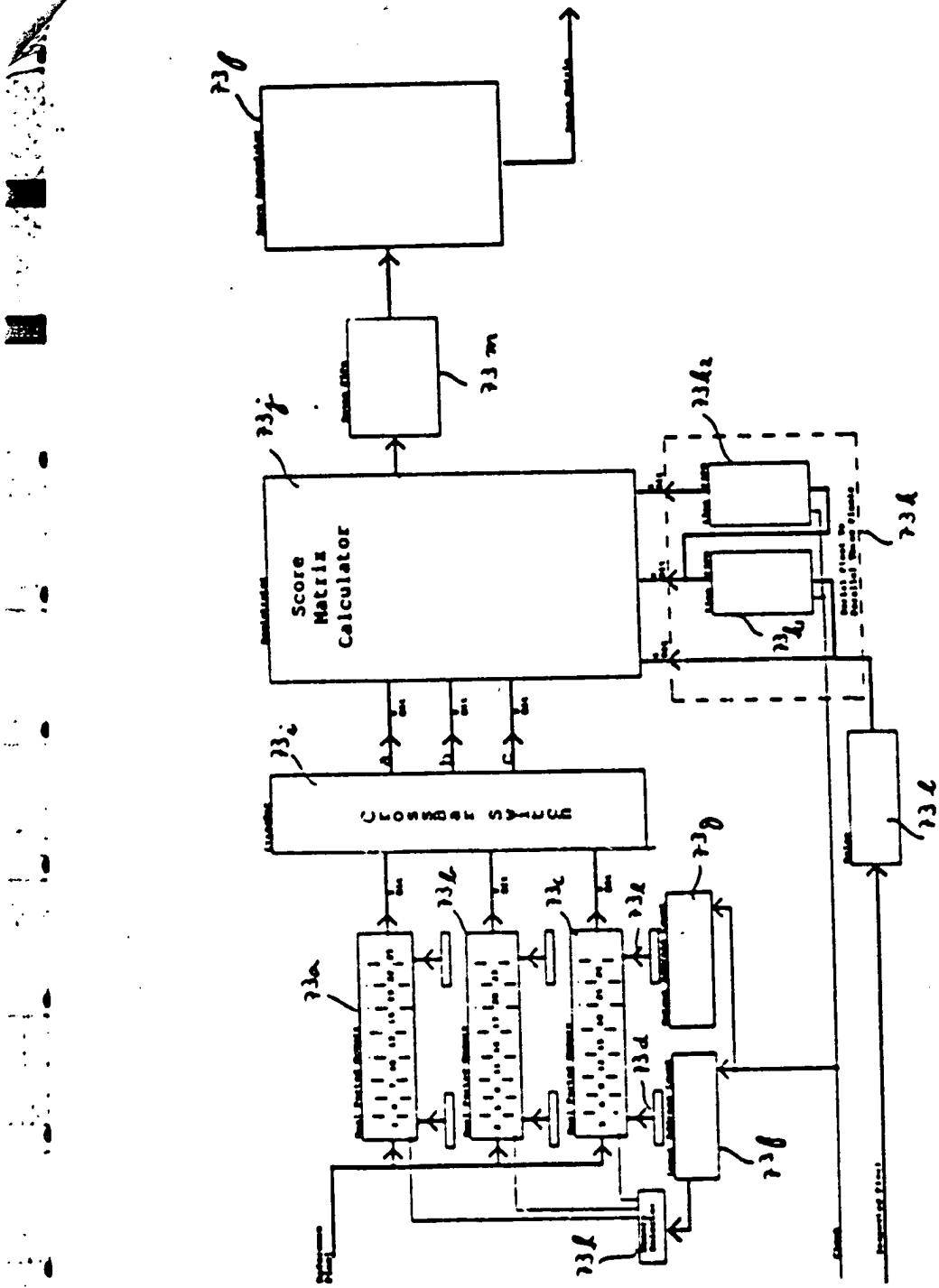
11/790871



Gradient Calculator

20/41

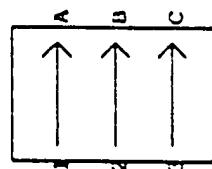
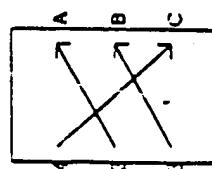
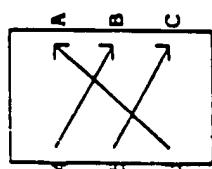
11/790871



Registration Score Matrix Calculator
Fig. 22

21/41

11/790871

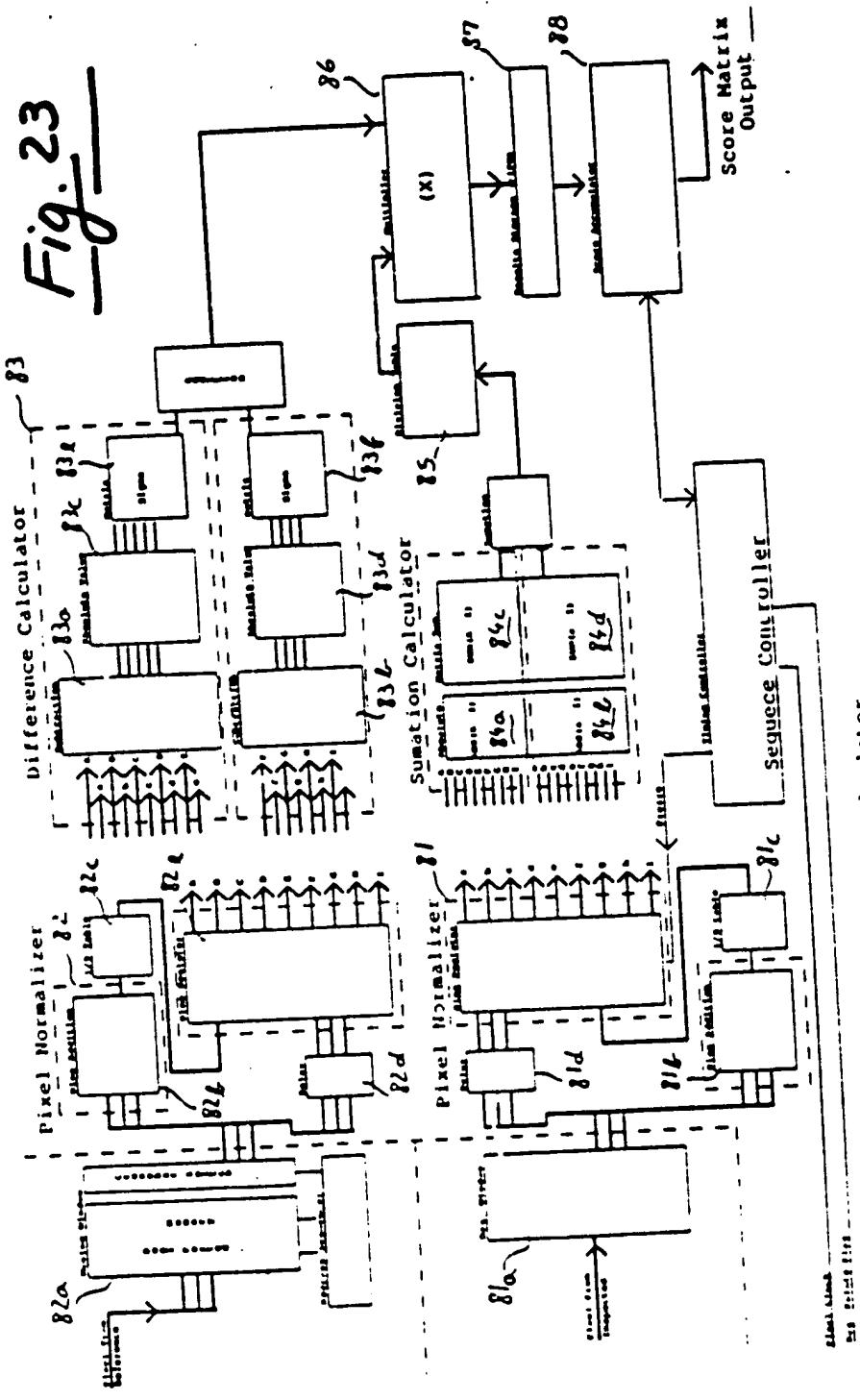


CrossBar Switch Combination

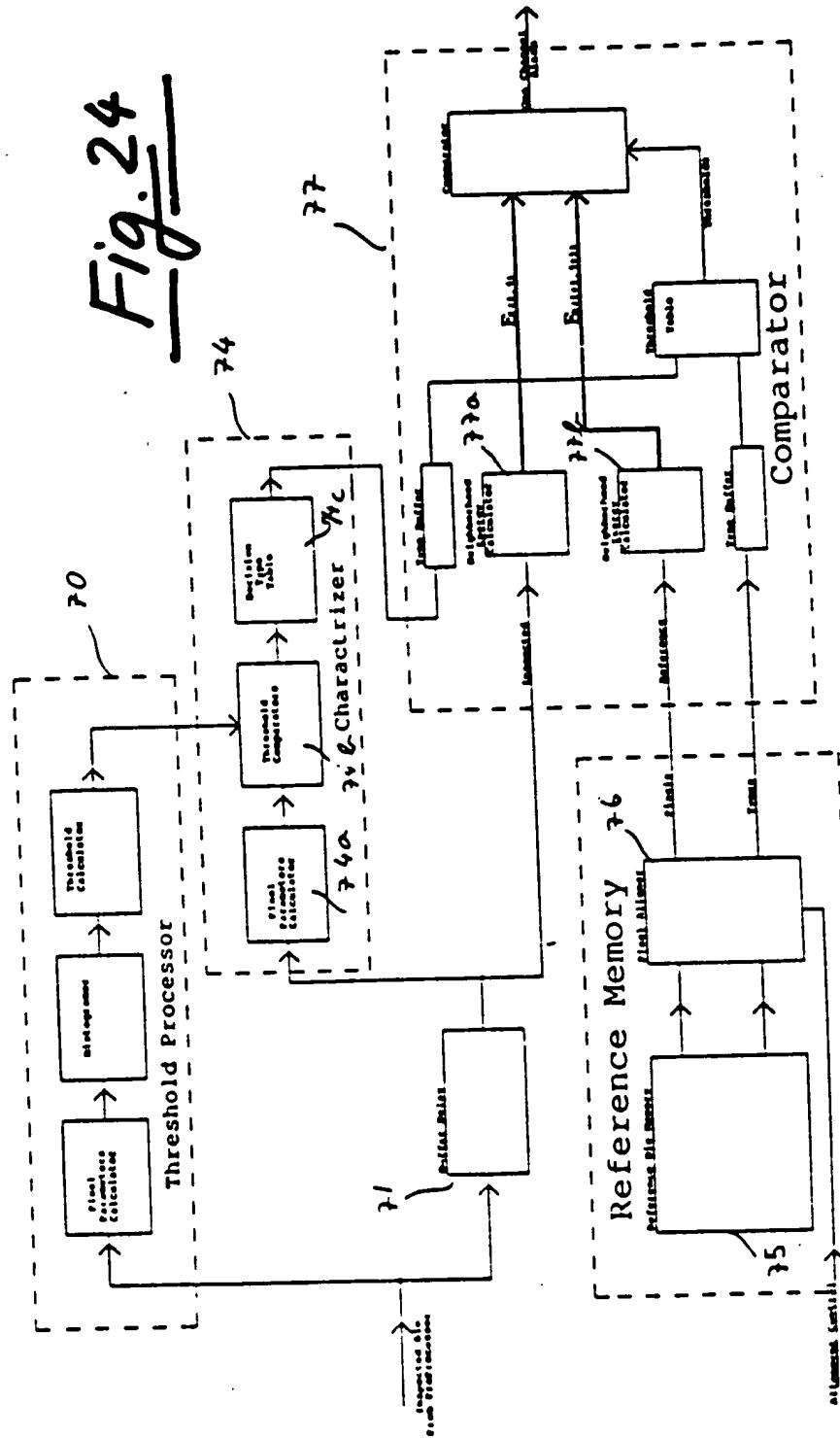
Fig. 22a

22/41

11/790871

Fig. 23

11/790871

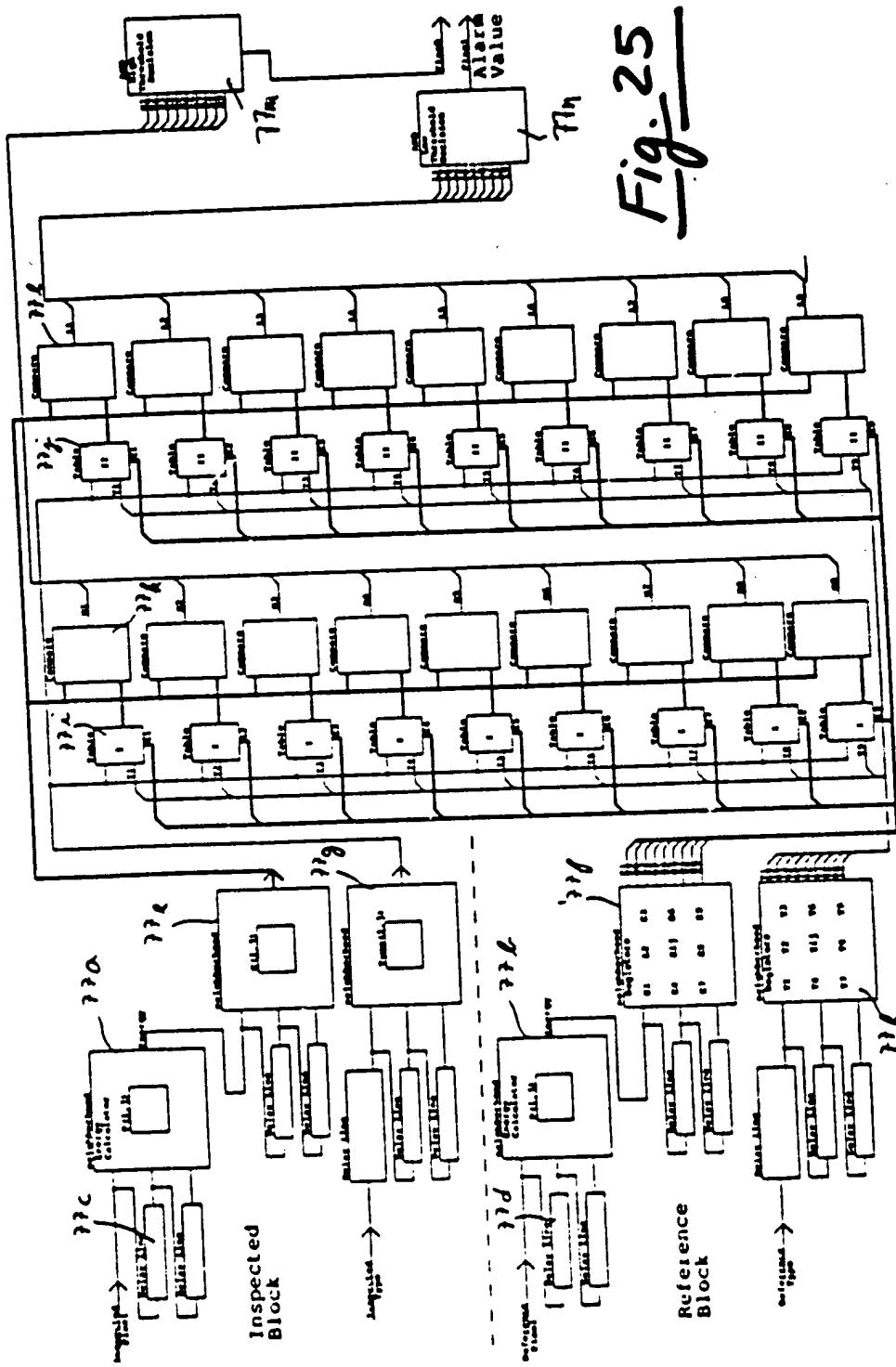
Fig. 24

Defect Detector Block Diagram

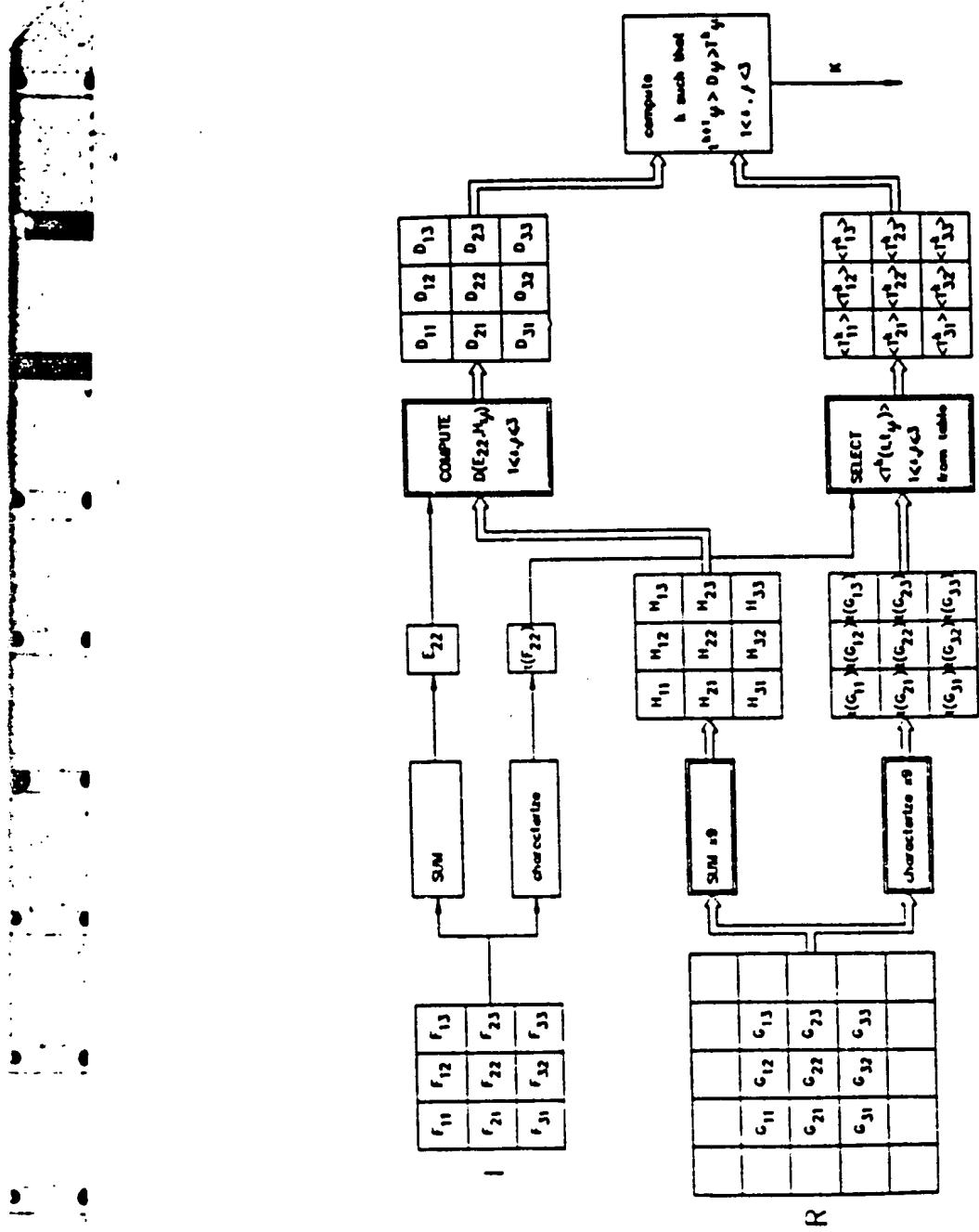
24/41

11-790871

Fig. 25



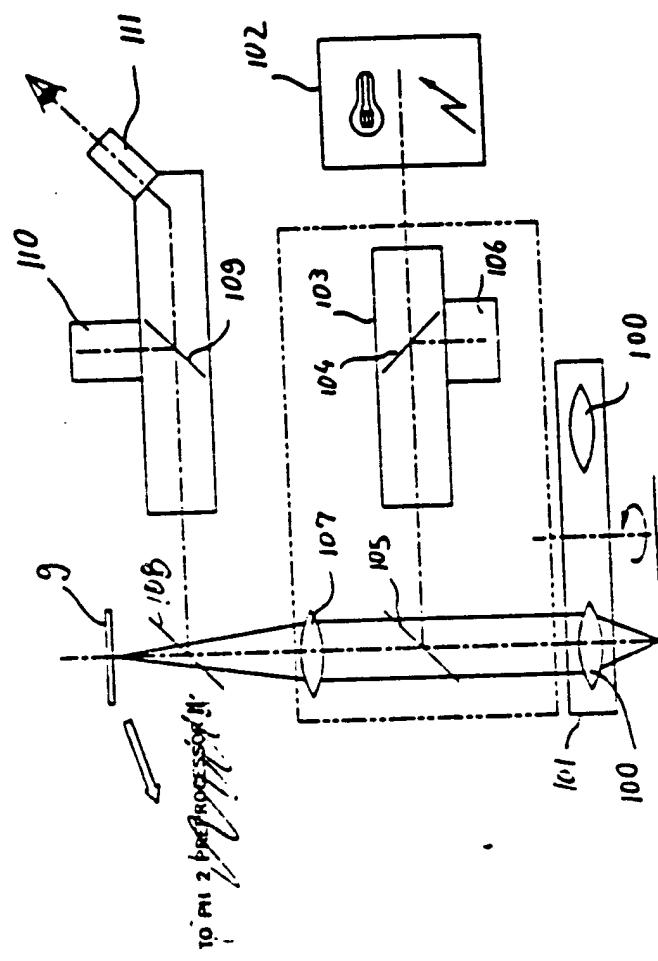
11/790871

Fig. 25a

26/41

11/790871

Fig. 26



23/41

11/790871

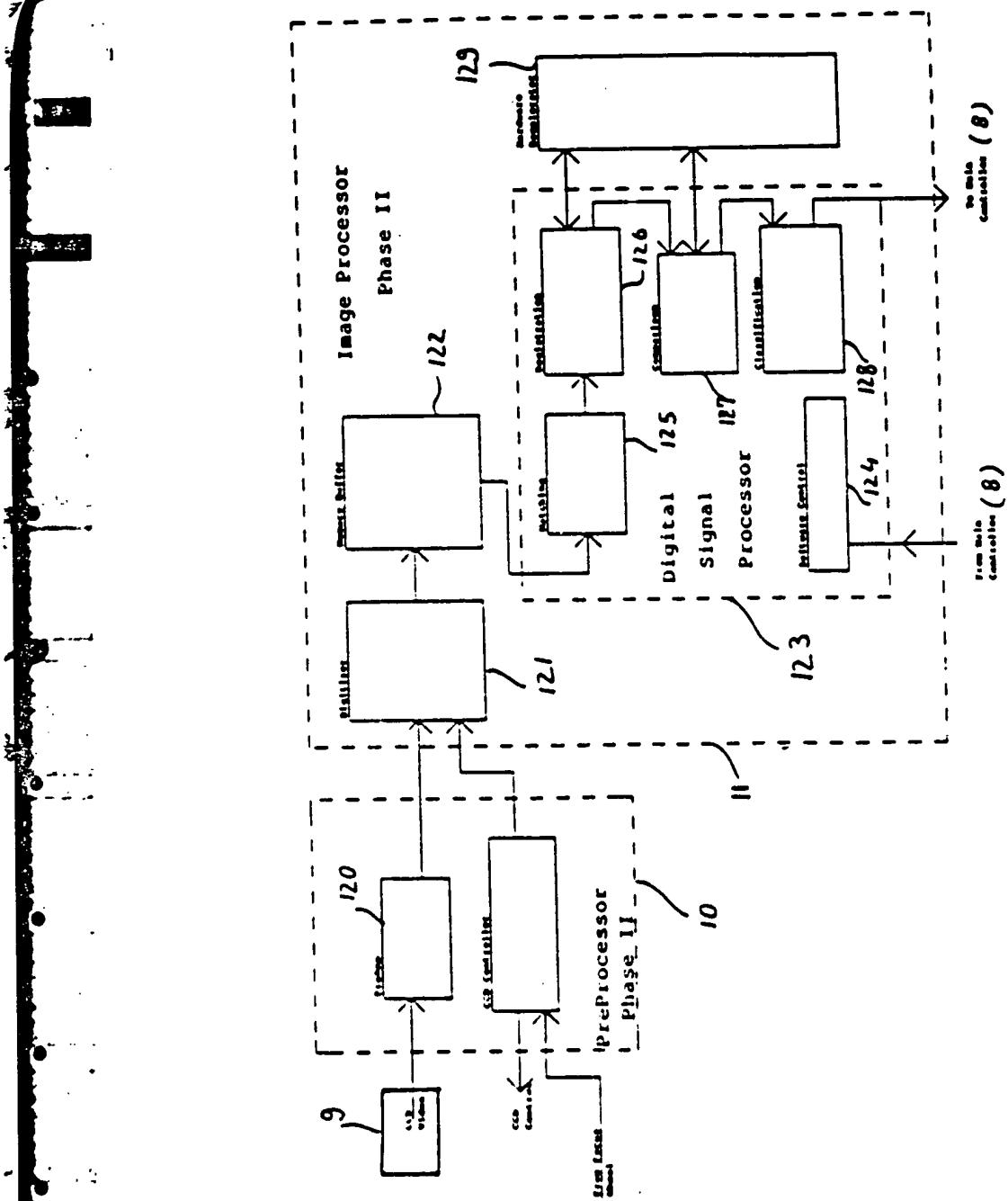


Fig. 27

11/790871 38/41

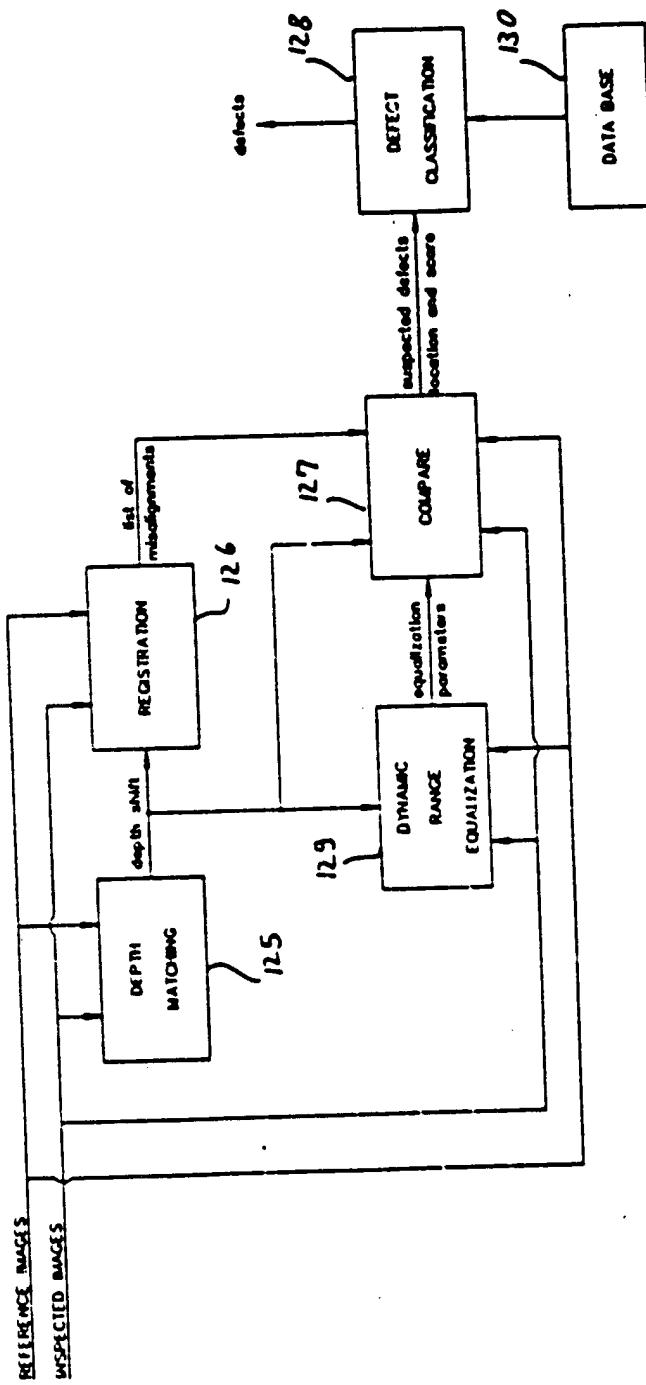
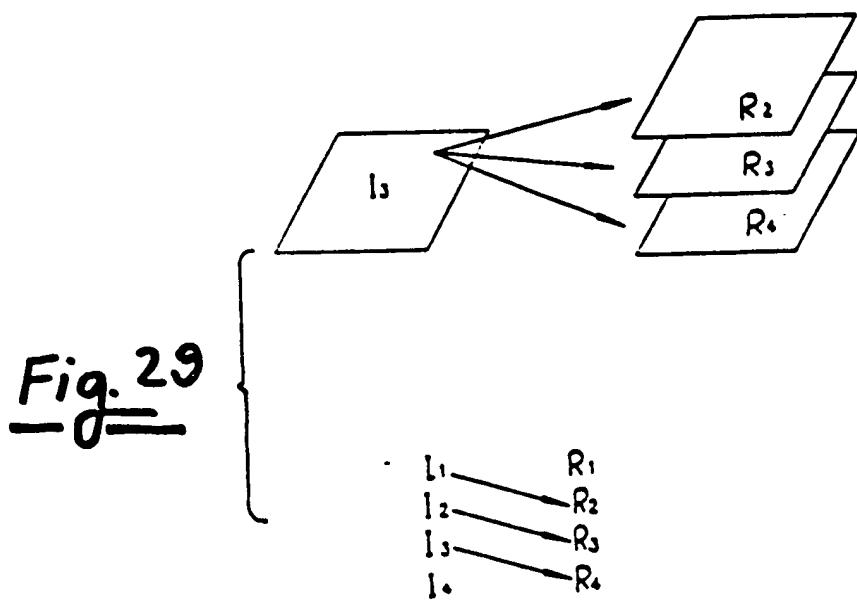


Fig. 28

29/41

11/790871



30/41

11/790871

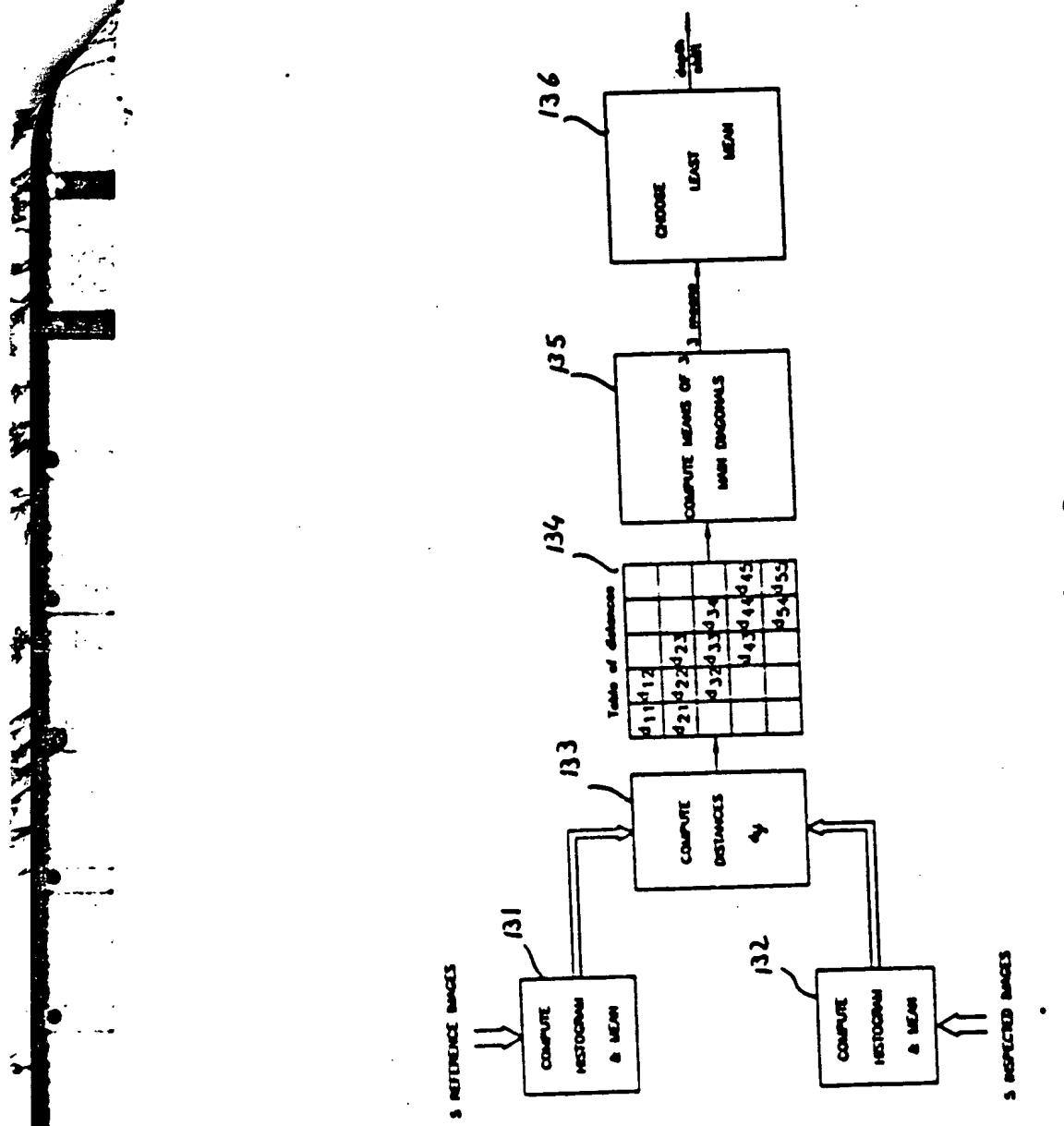


Fig. 30

31/41

11/790871

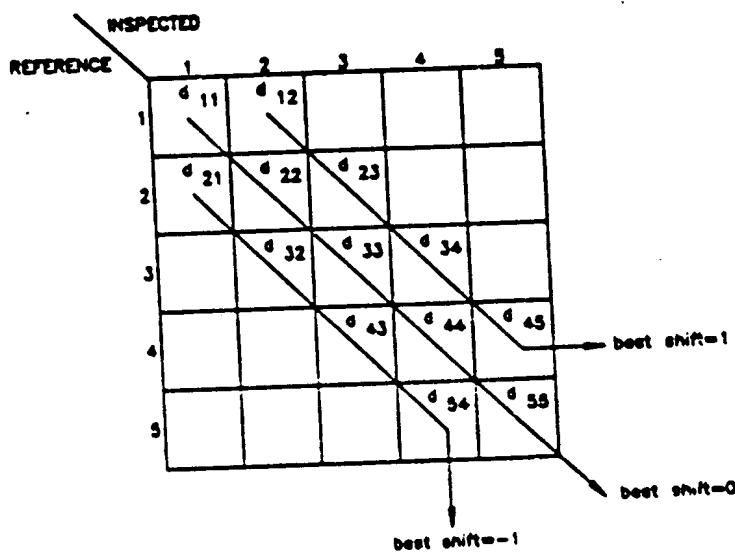


Fig. 31

11790871 32/41

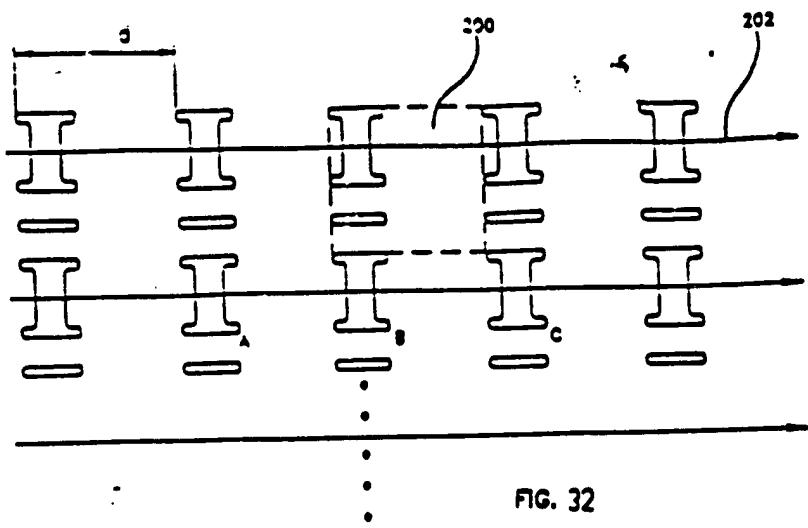


FIG. 32

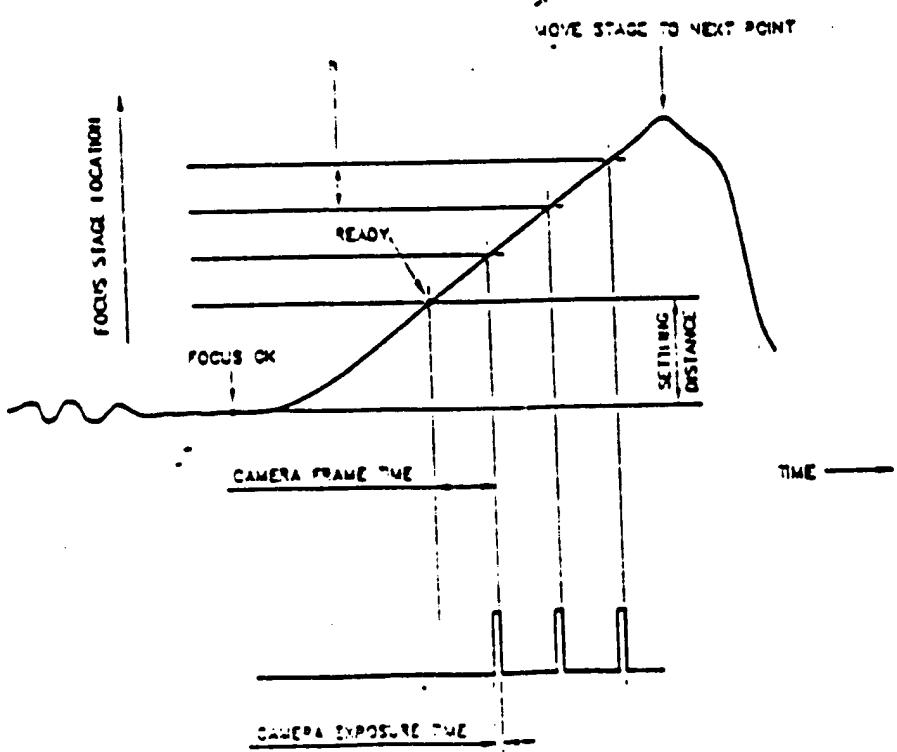


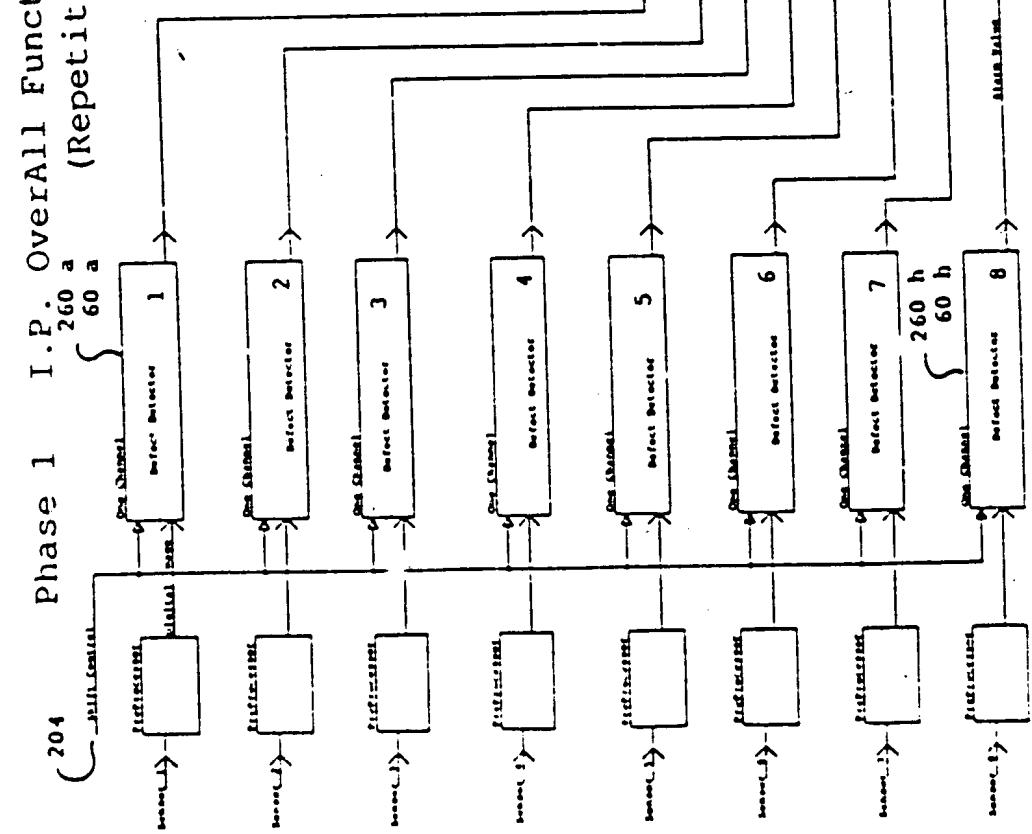
FIG. 37

11/790871

33/41

Phase 1 I.P. OverAll Functional Block Diagram
(Repetitive Pattern Inspection)

FIG. 33



204

204

Threshold
Processor

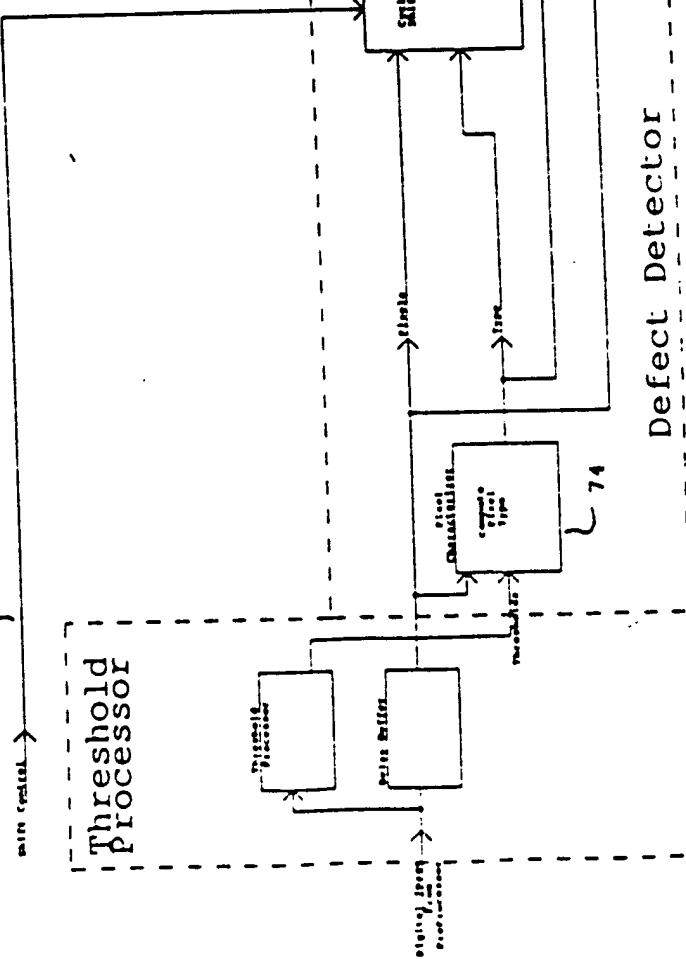
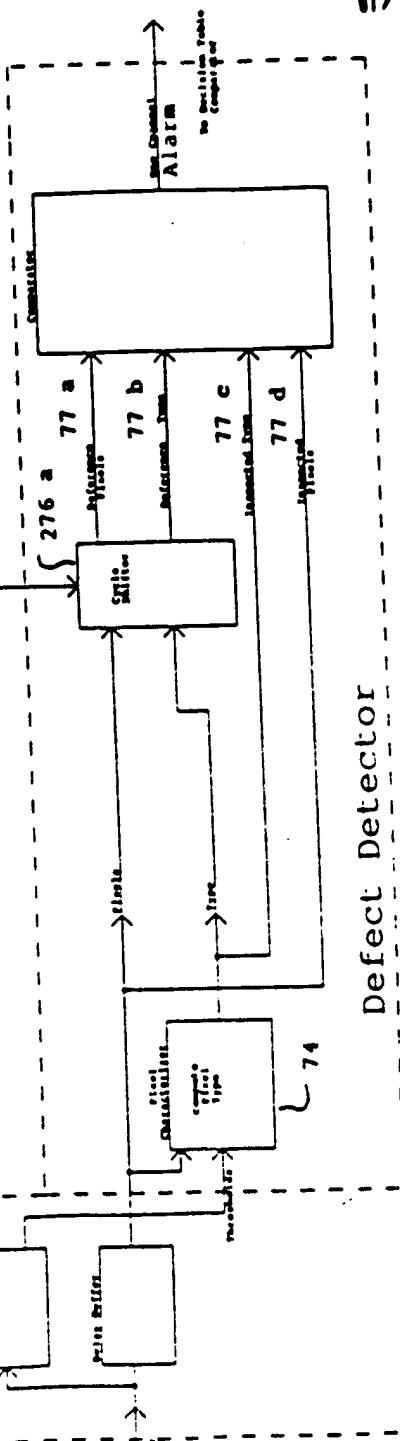


FIG. 34

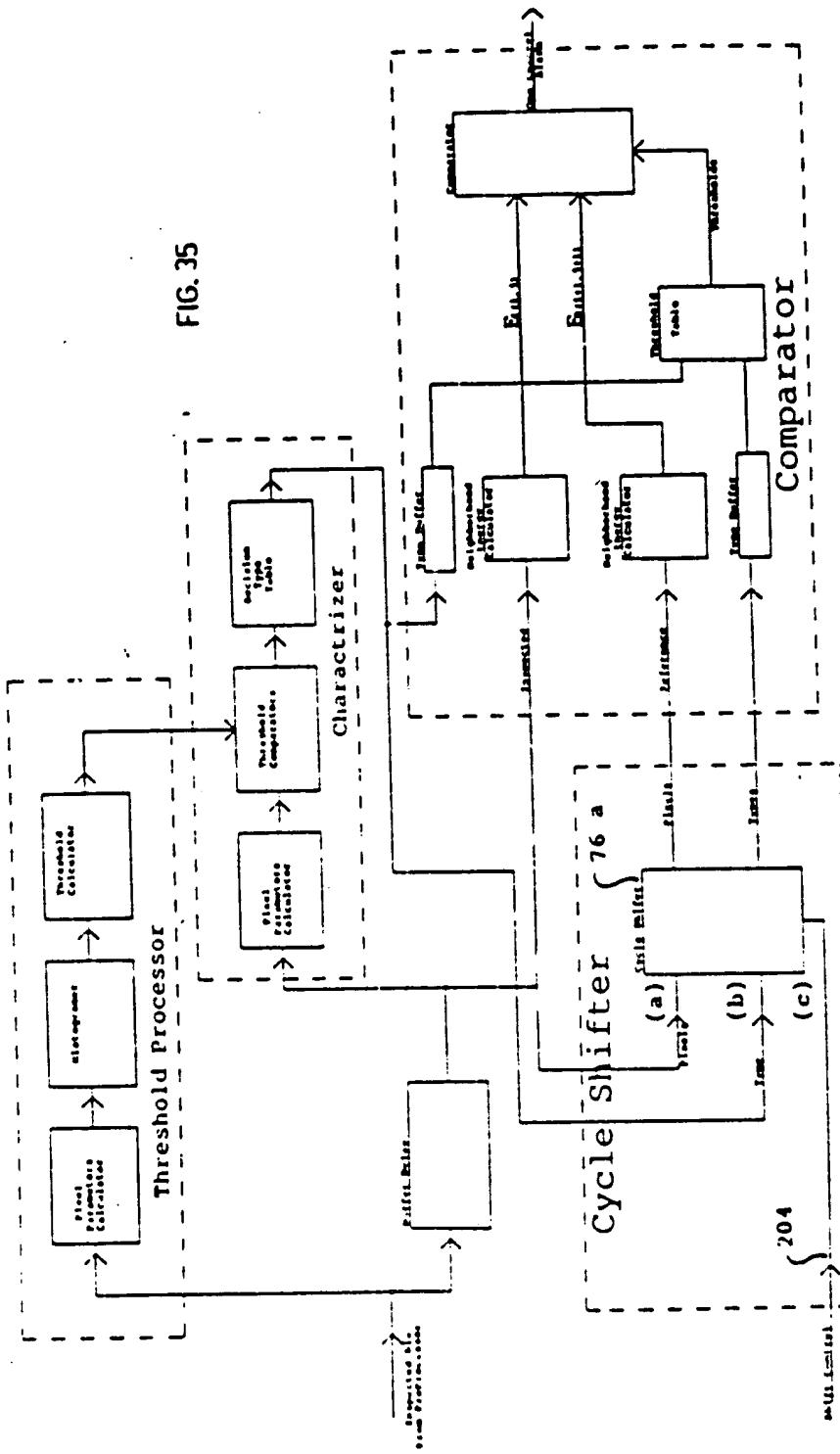


11/790871 34/41

One Channel I.P. Block Diagram
(Repetitive Pattern Inspection)

11/790871

FIG. 35



Defect Detector Block Diagram
(Repetitive Pattern Inspection)

117790871

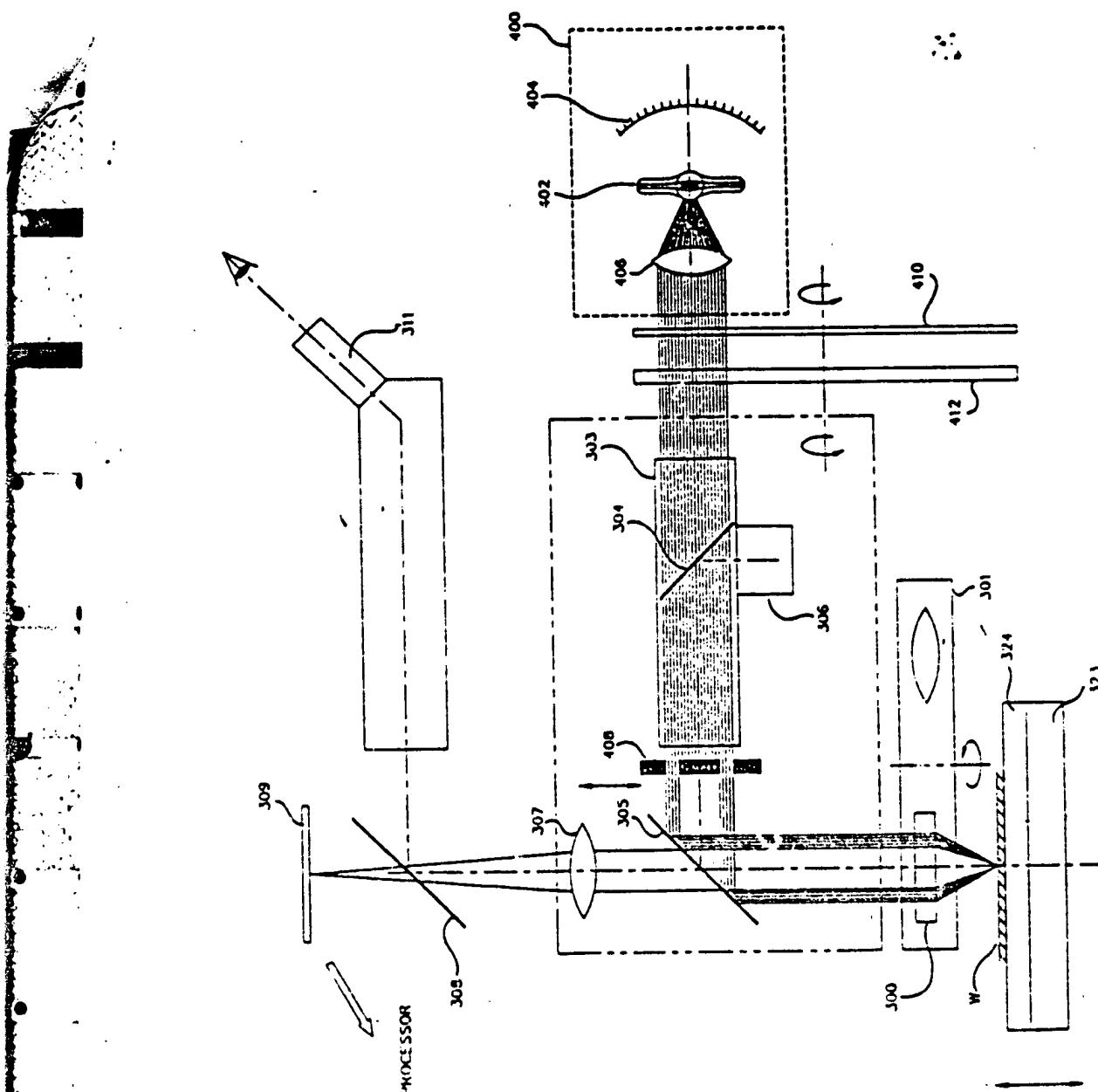


FIG. 36

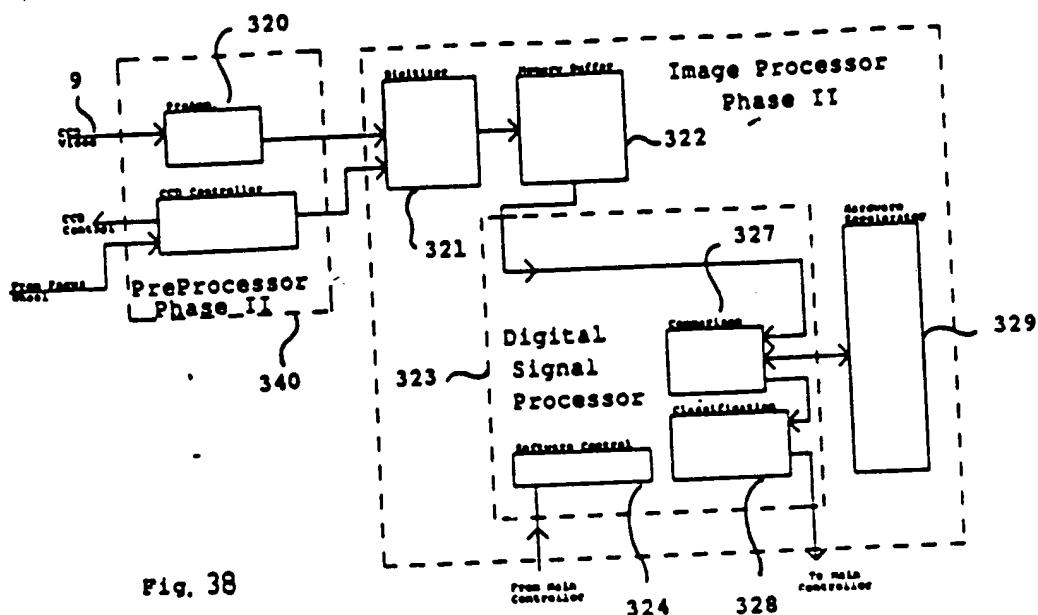


Fig. 38

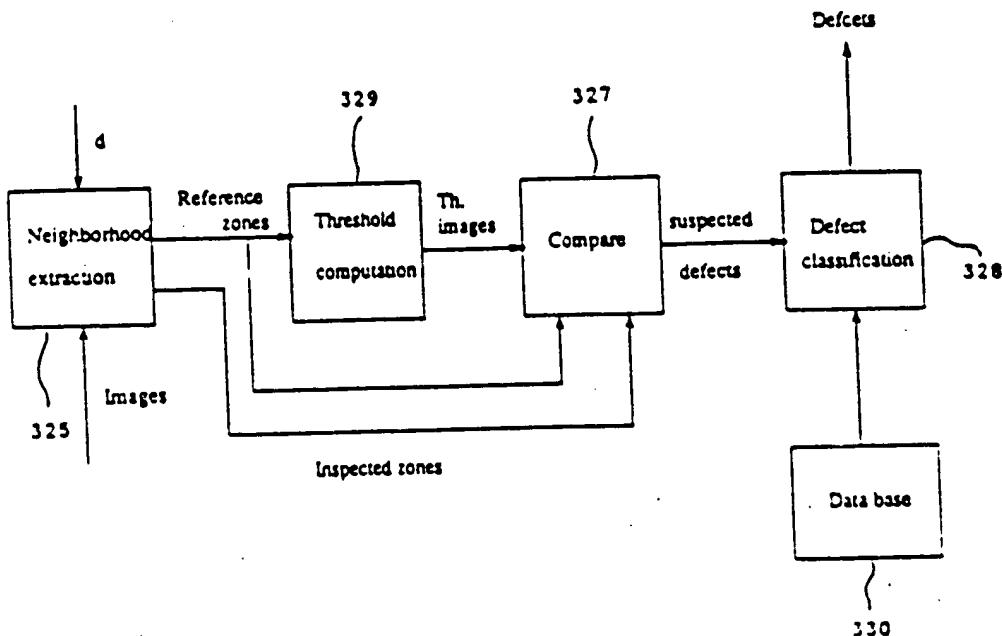


Fig. 39

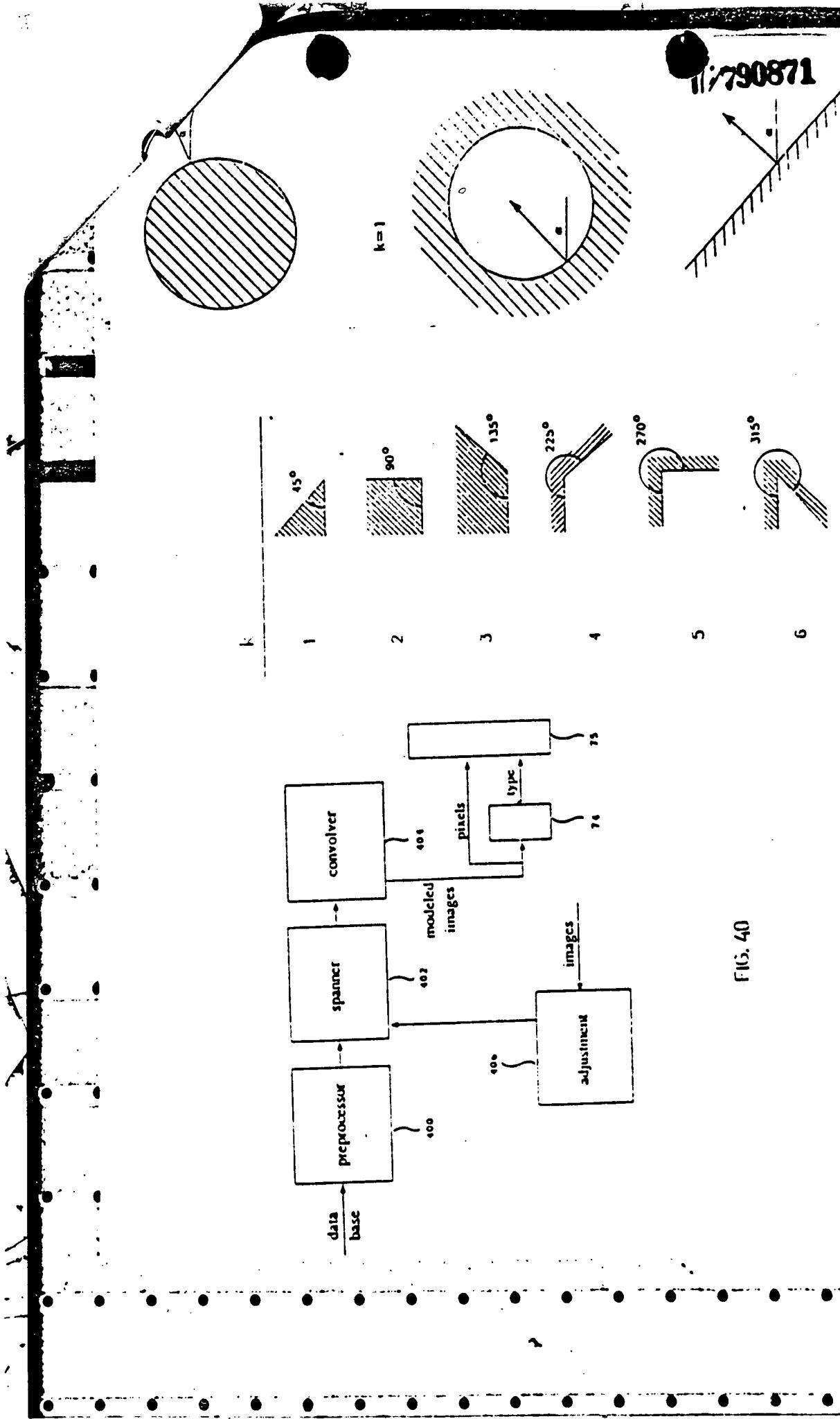


FIG. 42

k=3

FIG. 41

FIG. 40

39/41

11/790871

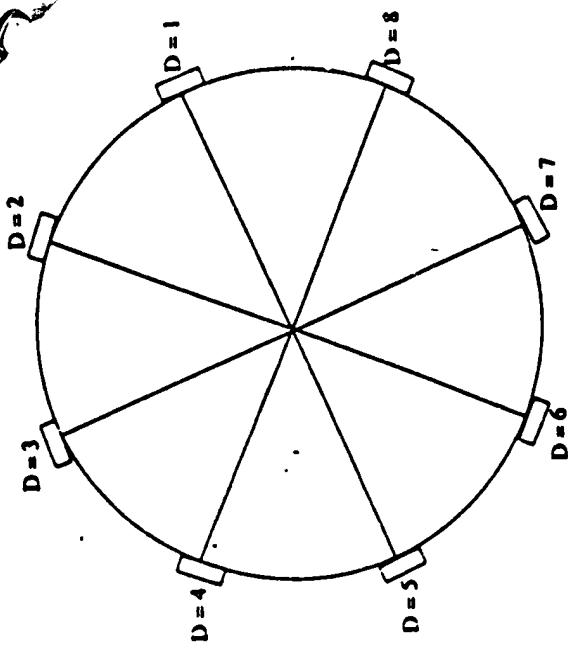
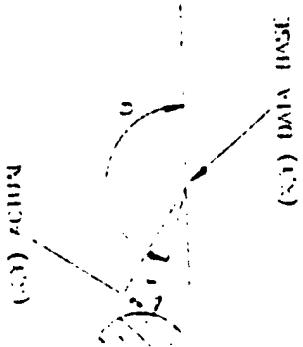


Fig. 43



CORNER SHIFT

FIG. 44

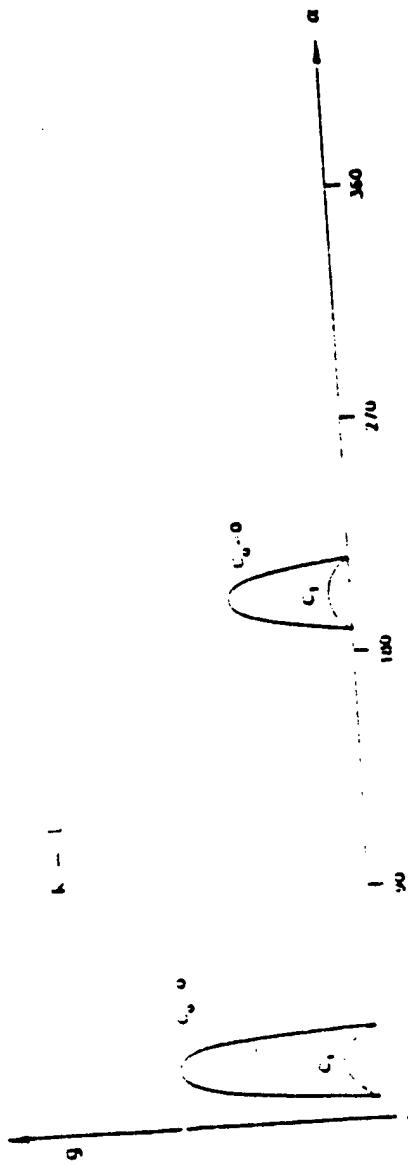


FIG. 45

11/790871

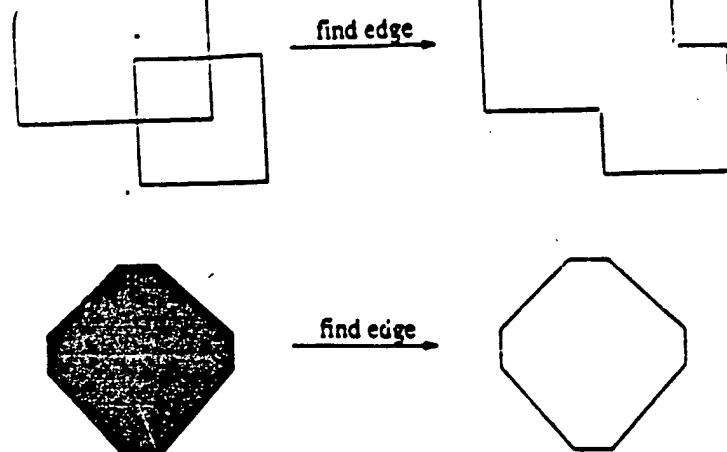


Fig. 46

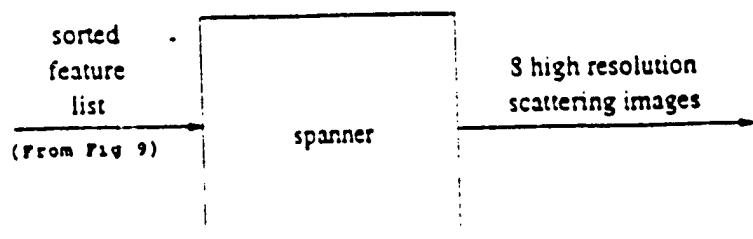
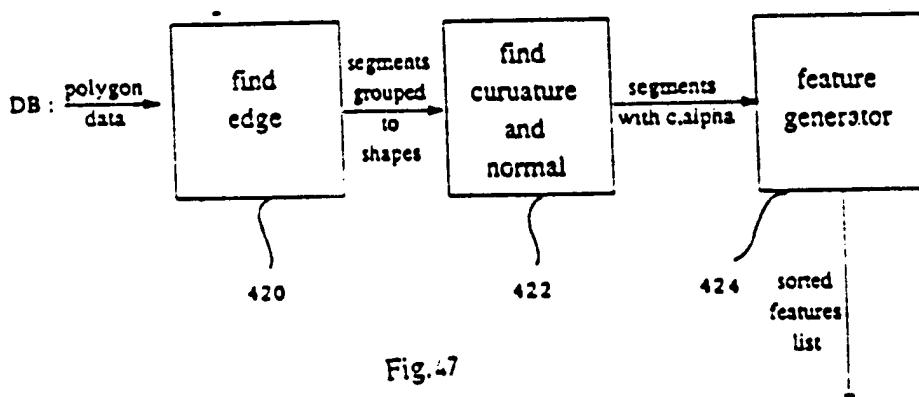


Fig. 48

117790871

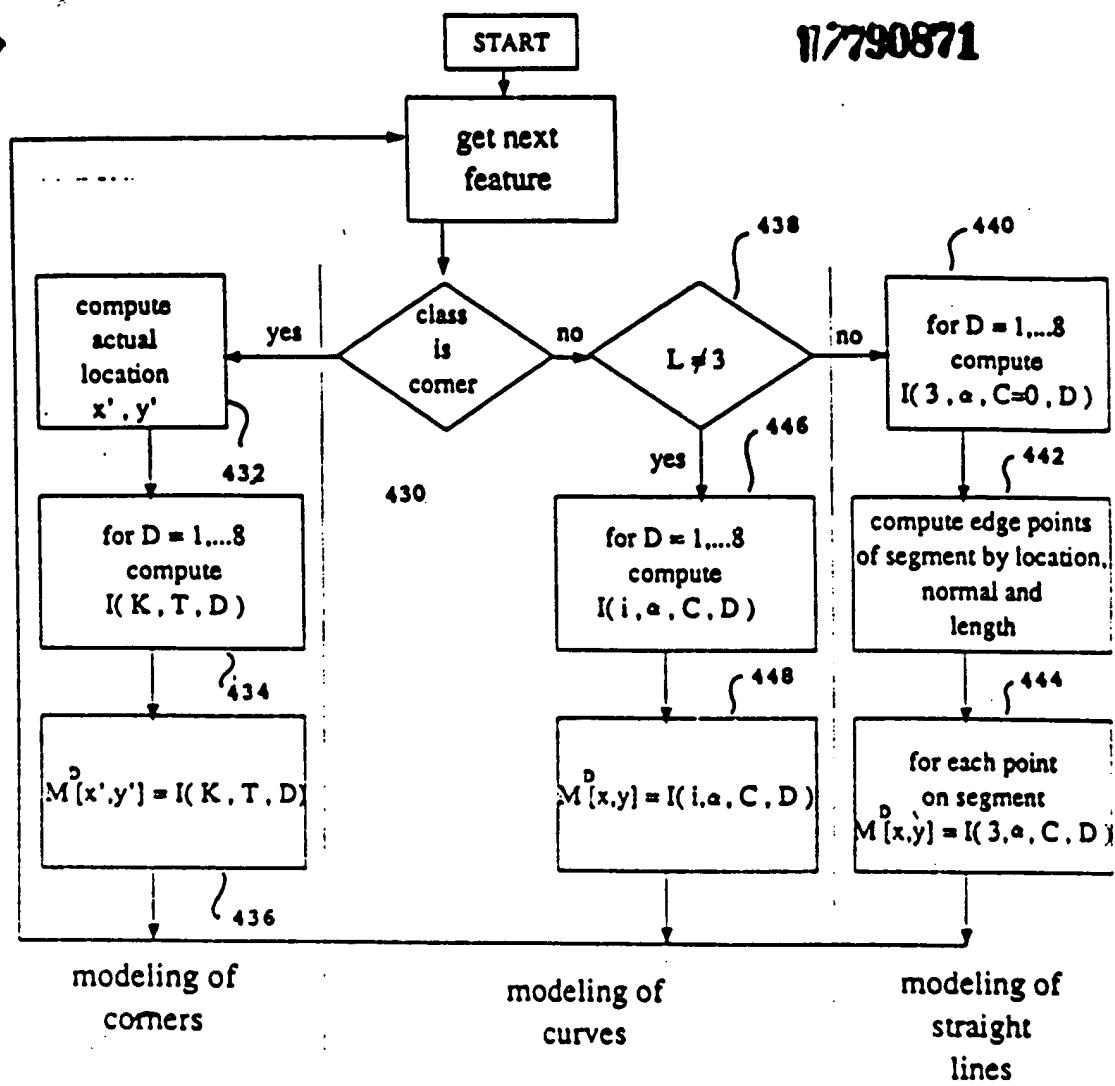


Fig.29 : spanner flow-chart

**This Page is Inserted by IFW Indexing and Scanning
Operations and is not part of the Official Record**

BEST AVAILABLE IMAGES

Defective images within this document are accurate representations of the original documents submitted by the applicant.

Defects in the images include but are not limited to the items checked:

- BLACK BORDERS**
- IMAGE CUT OFF AT TOP, BOTTOM OR SIDES**
- FADED TEXT OR DRAWING**
- BLURRED OR ILLEGIBLE TEXT OR DRAWING**
- SKEWED/SLANTED IMAGES**
- COLOR OR BLACK AND WHITE PHOTOGRAPHS**
- GRAY SCALE DOCUMENTS**
- LINES OR MARKS ON ORIGINAL DOCUMENT**
- REFERENCE(S) OR EXHIBIT(S) SUBMITTED ARE POOR QUALITY**
- OTHER:** _____

IMAGES ARE BEST AVAILABLE COPY.

As rescanning these documents will not correct the image problems checked, please do not report these problems to the IFW Image Problem Mailbox.